

Event driven Timepix3 hybrid pixel detector for cryo-EM at 200 kV

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Meeting: Riva del Garda

Date 27-06-2022

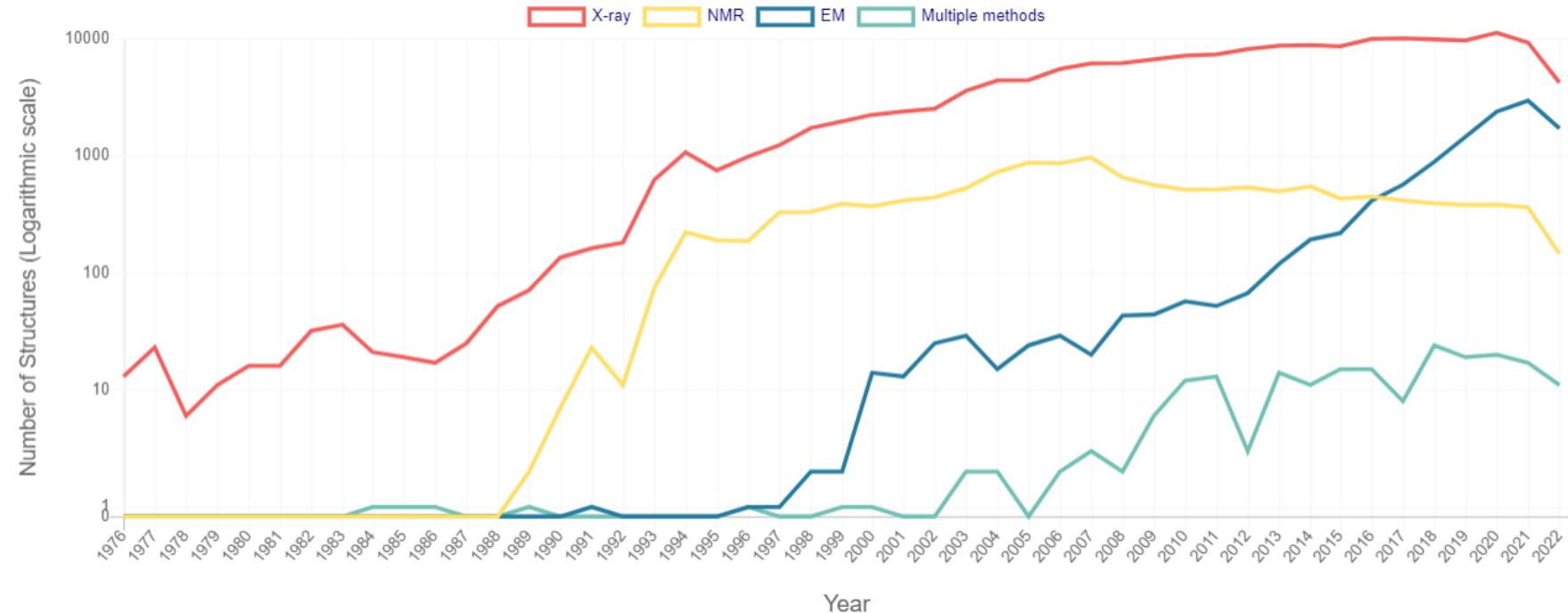
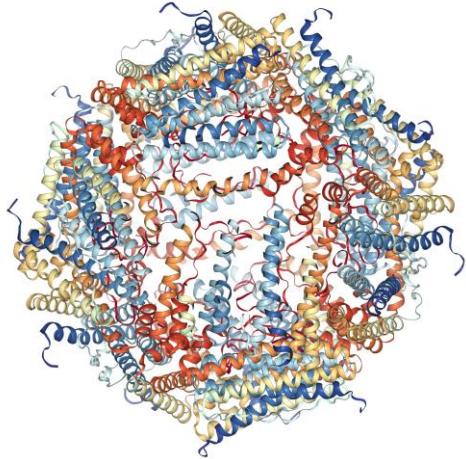


Maastricht University

M4i

Cryogenic Transmission Electron Microscopy for Structural Biology

Number of Structures in Protein Data Bank



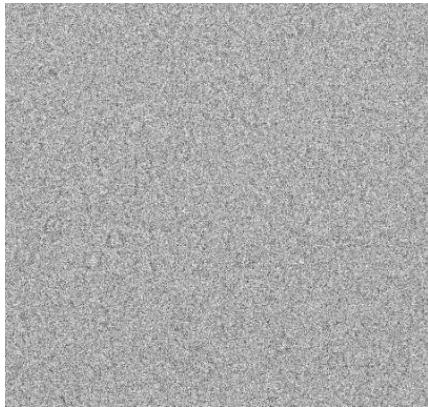
191565 Biological
Macromolecular Structures
Enabling Breakthroughs in
Research and Education



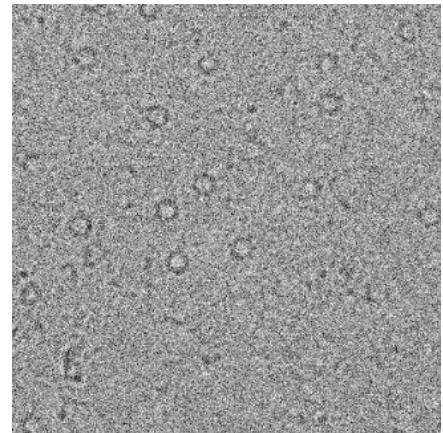
- EXPERIMENTAL METHOD
- X-RAY DIFFRACTION (1409)
 - ELECTRON MICROSCOPY (780)
 - SOLUTION NMR (9)
 - NEUTRON DIFFRACTION (7)
 - SOLID-STATE NMR (2)

Why detectors?

Weak phase objects



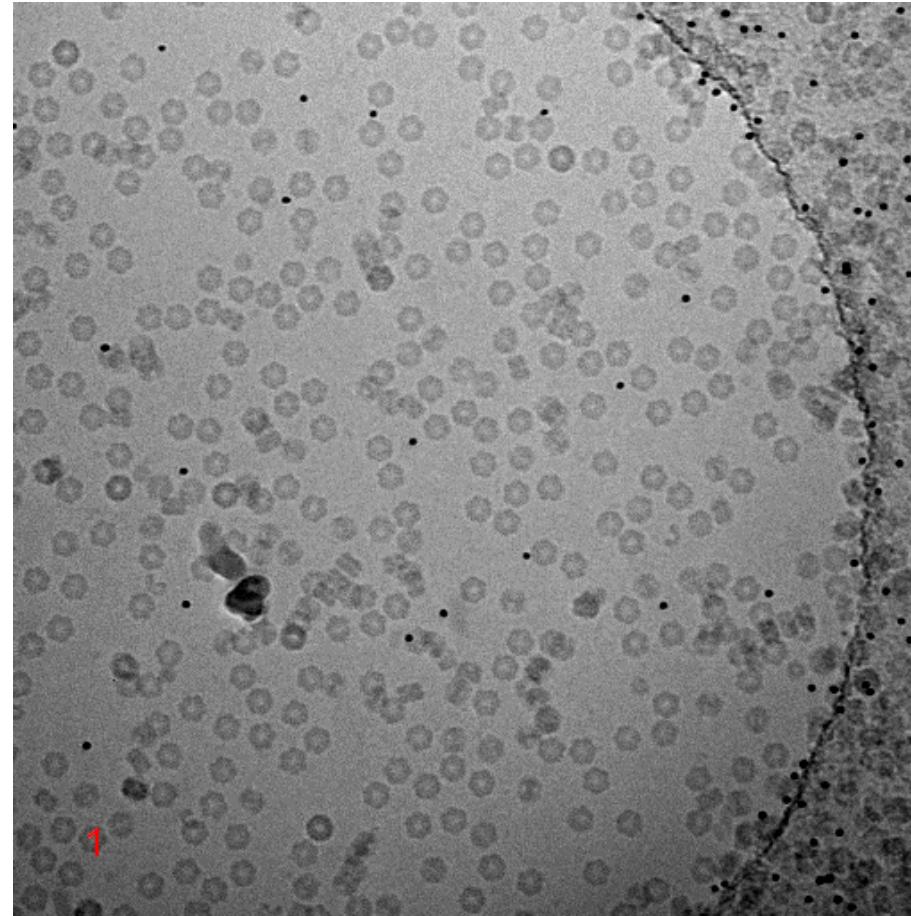
$\Delta f = -0.6 \text{ } \mu\text{m}$



$\Delta f = -2.3 \text{ } \mu\text{m}$

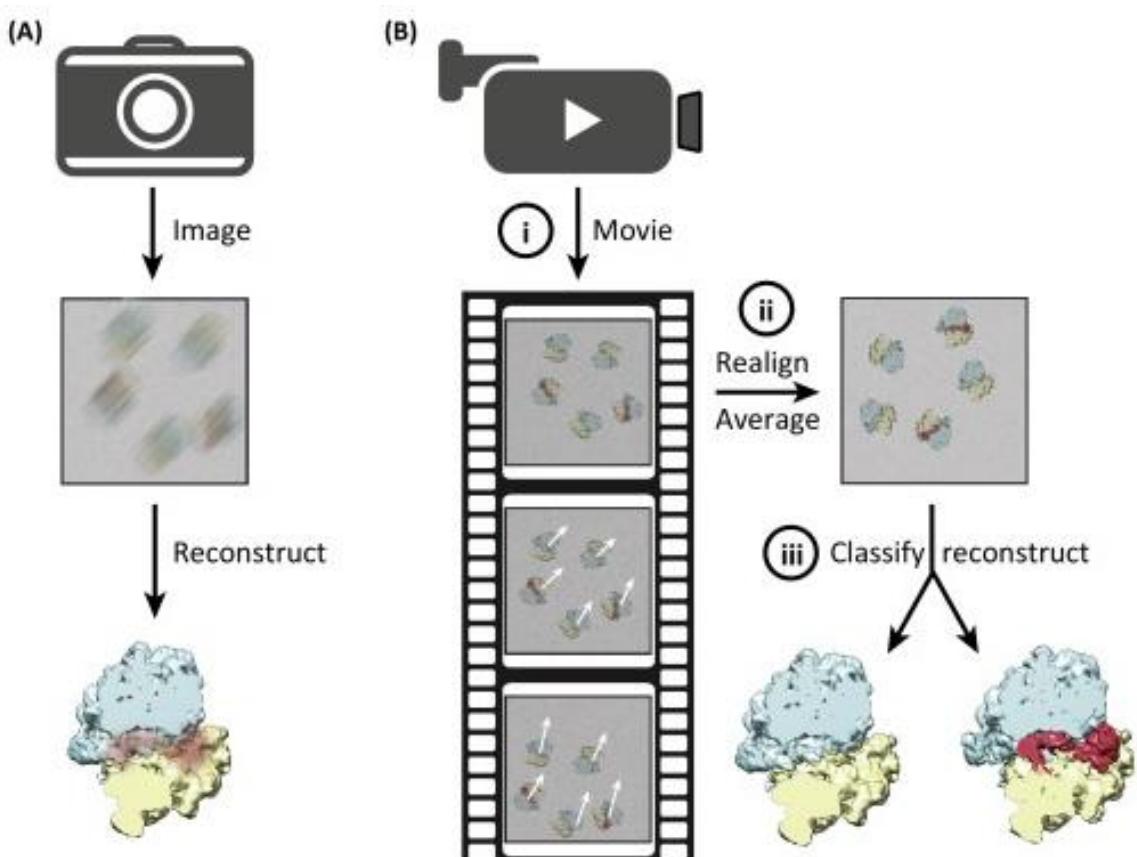
High defocus

Radiation damage



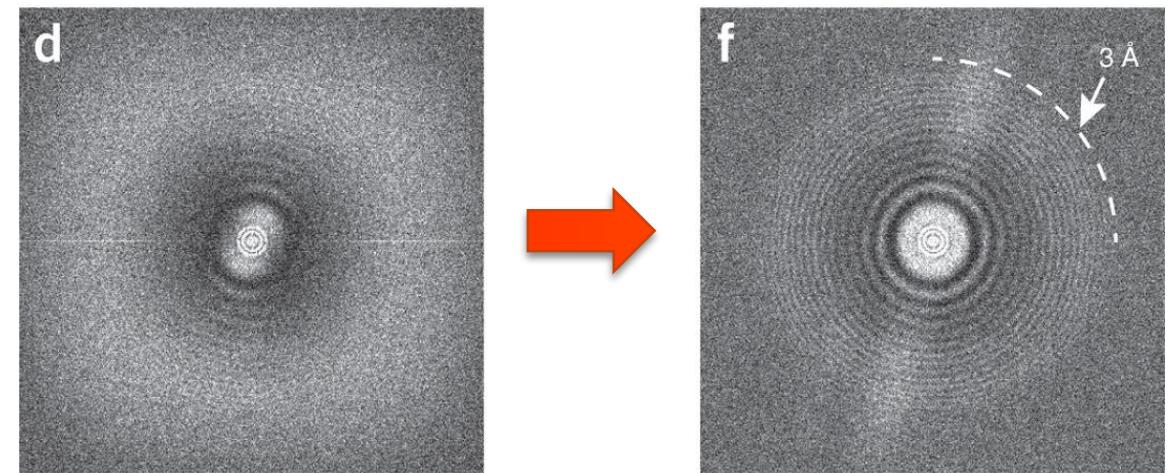
Flux: $50 \text{ e} \cdot \text{\AA}^{-2} \text{ s}^{-1}$, 100 images, 1 s integration time each.

Detector makes the difference

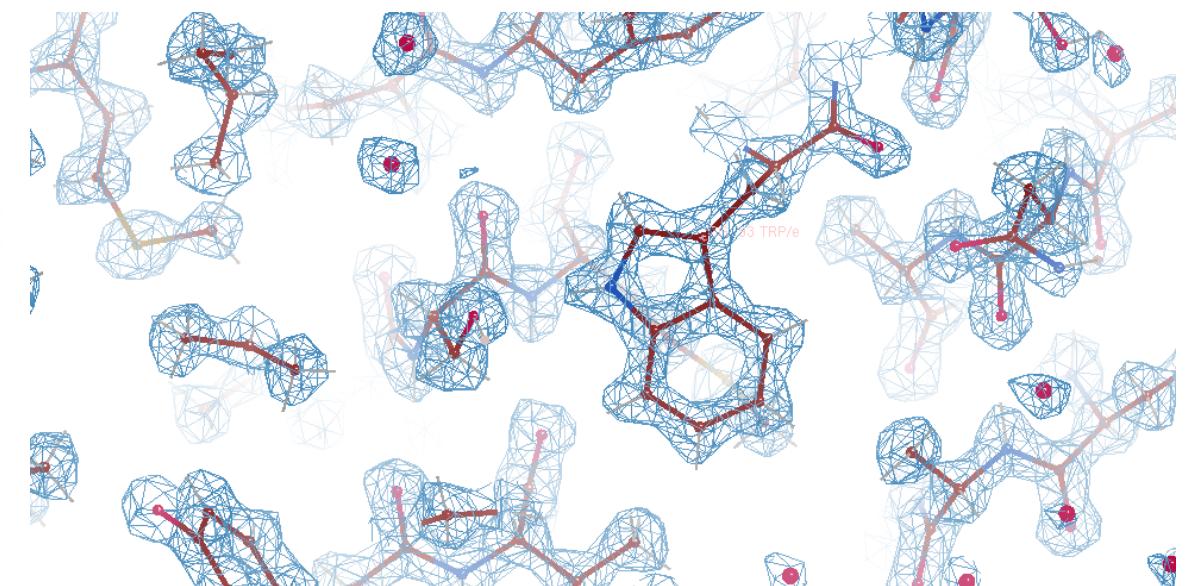


Bai et al., 2015

TIBS



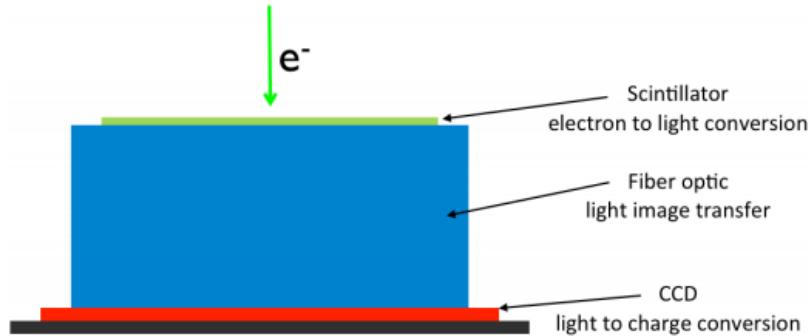
Li et al., 2015



Yip et al., 2020

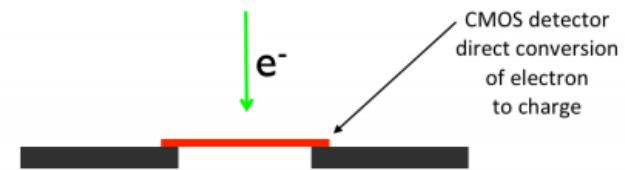
Type of electron detectors

Charge Coupled Device (CCD)



Scintillator adds noise
Scintillator deteriorate PSF
Limited dynamic range
Readout noise

Monolithic Active Pixel Sensor (MAPS)



Frame based
Low throughput ~ 40 s
0.01–0.025 electrons/pixel/frame
Works best at 300 kV
Radiation sensitive
Limited dynamic range

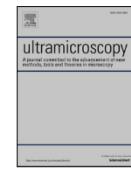
Better detector for cryo-EM?



Contents lists available at ScienceDirect

Ultramicroscopy

journal homepage: www.elsevier.com/locate/ultramic



The energy dependence of contrast and damage in electron cryomicroscopy of biological molecules

Mathew J. Peet, Richard Henderson, Christopher J. Russo*

MRC Laboratory of Molecular Biology, Francis Crick Avenue, Cambridge CB2 0QH, UK

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Serial protein crystallography in an electron microscope

Robert Bücker, Pascal Hogan-Lamarre, Pedram Mehrabi, Eike C. Schulz, Lindsey A. Bultema, Yaroslav Gevorkov, Wolfgang Brehm, Oleksandr Yefanov, Dominik Oberthür, Günther H. Kassier & R. J. Dwayne Miller✉

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JOURNAL OF
SYNCHROTRON
RADIATION

ISSN 1600-5775

radiation damage

Single-particle cryo-EM: alternative schemes to improve dose efficiency

Yue Zhang,^a Peng-Han Lu,^b Enzo Rotunno,^c Filippo Troiani,^c J. Paul van Schayck,^a Amir H. Tavabi,^b Rafal E. Dunin-Borkowski,^b Vincenzo Grillo,^c Peter J. Peters^a and Raimond B. G. Ravelli^{a*}

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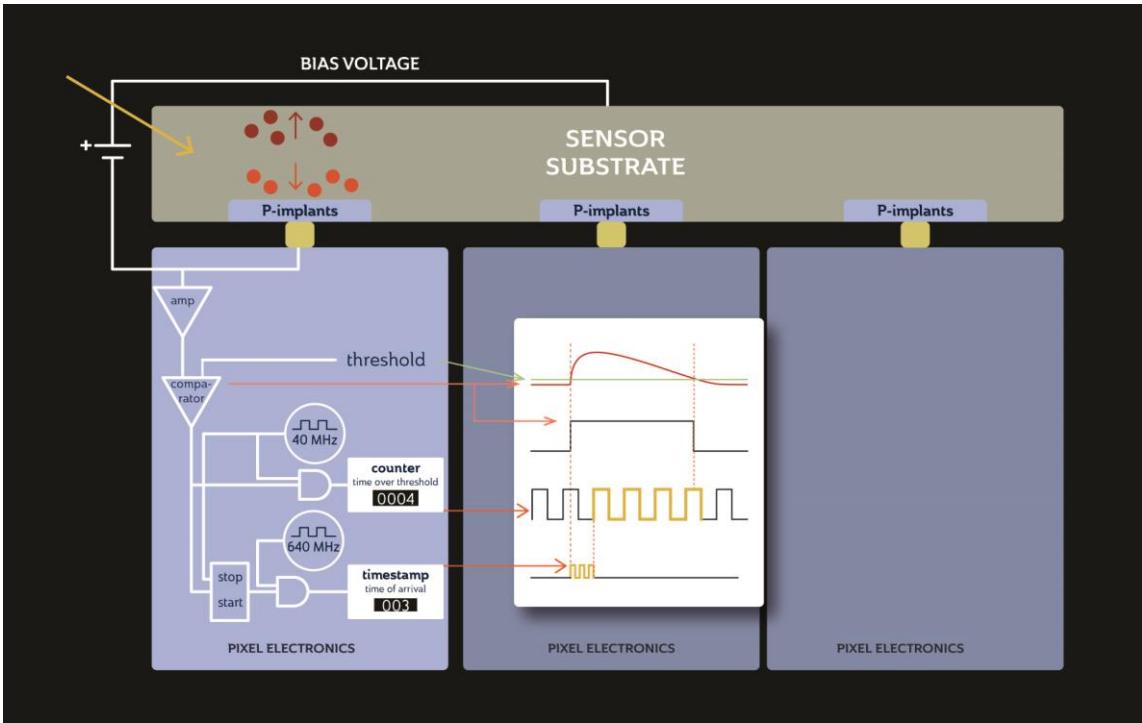
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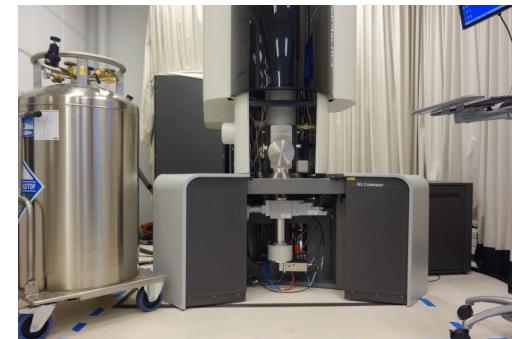
Low-dose phase retrieval of biological specimens using cryo-electron ptychography

Liqi Zhou, Jingdong Song, Judy S. Kim, Xudong Pei, Chen Huang, Mark Boyce, Luiza Mendonça, Daniel Clare, Alistair Siebert, Christopher S. Allen, Emanuela Liberti, David Stuart, Xiaoqing Pan, Peter D. Nellist, Peijun Zhang, Angus I. Kirkland✉ & Peng Wang✉

Timepix3: An event driven Hybrid Pixel Detector



- Event driven
- Radiation hard
- Simultaneous readout of
 - Time over Threshold (energy)
 - Time of Arrival (timing)
- 640 MHz clock
- 120 Mhit/s (quad)
- Noiseless readout



SPIDR readout from Nikhef.



Mounted on FEI Tecnai Arctica (200 kV)

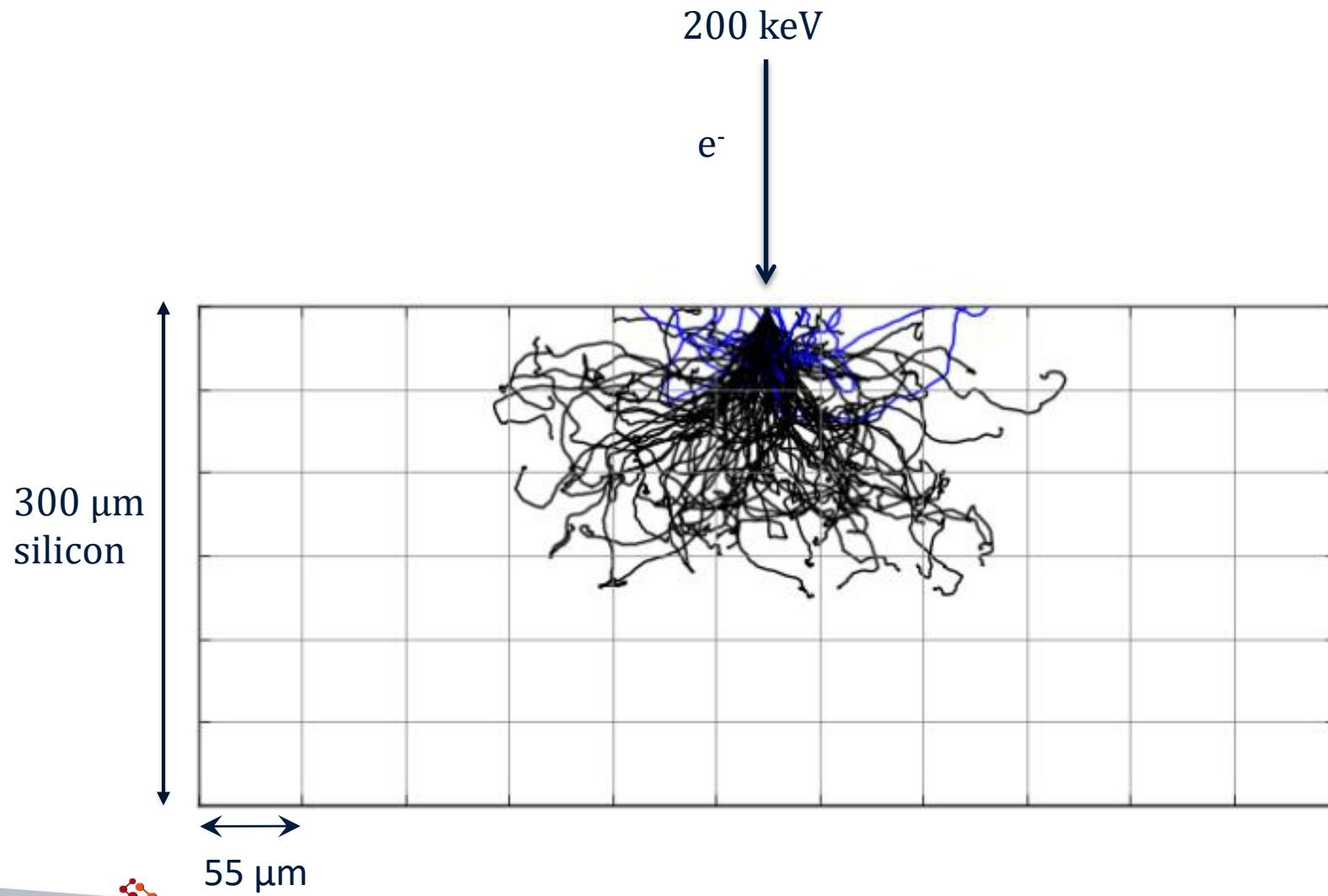
Integration of an event-driven Timepix3 hybrid pixel detector into a cryo-EM workflow

1. Event localisation of electrons
2. Measuring MTF, NPS and DQE
3. Correcting for chip edge
4. Integration of Timepix3 in SerialEM and microscope for automated data collection
5. Single particle analysis

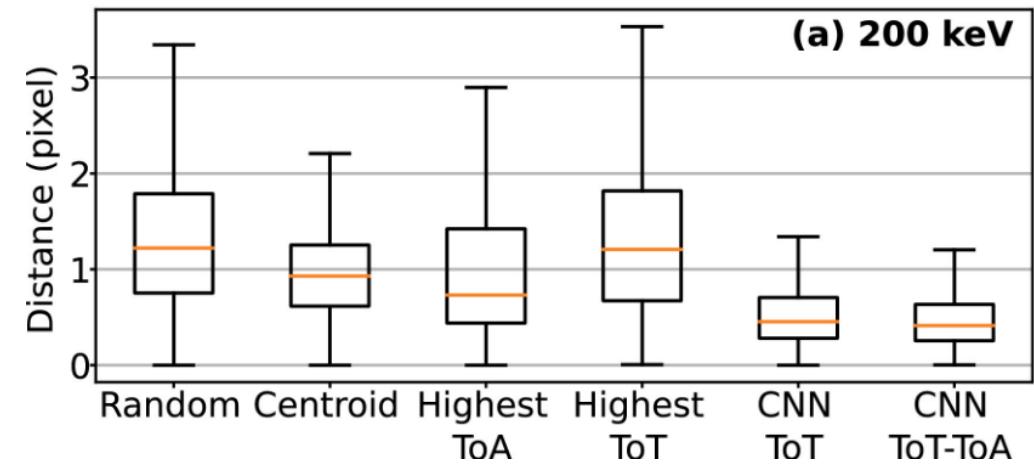
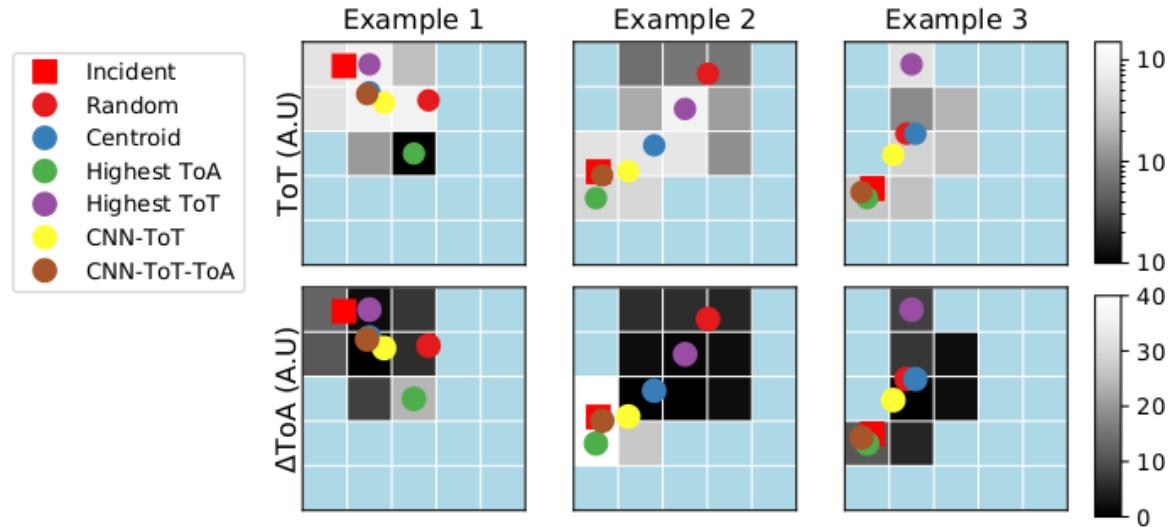
Timepix3 for cryo-EM

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The challenge of detecting electrons in their incident position



Localising the incident position using Timepix3

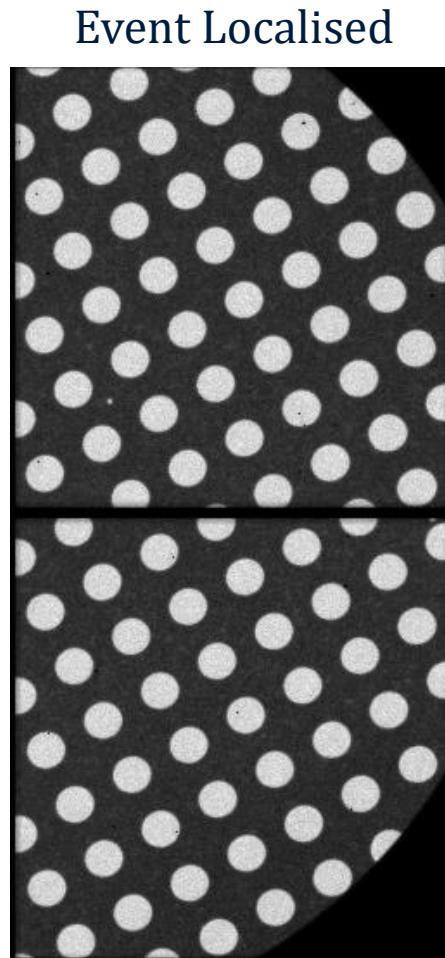
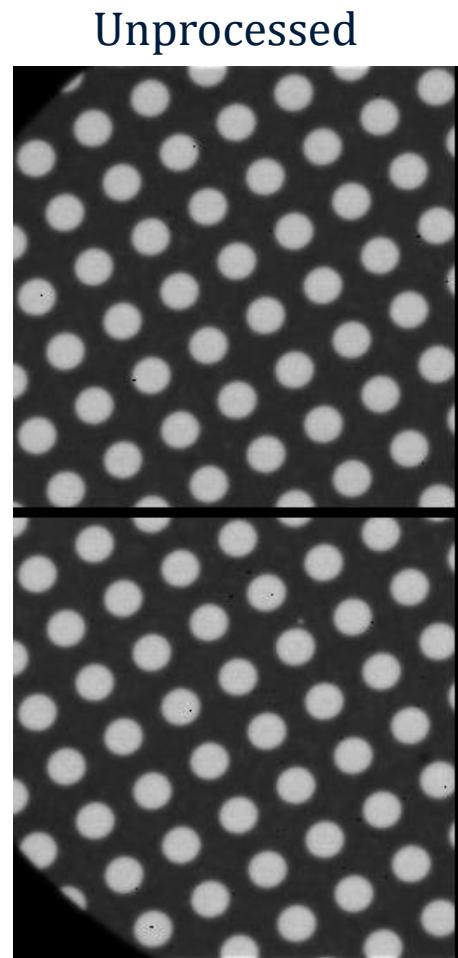


van Schayck et al., 2020

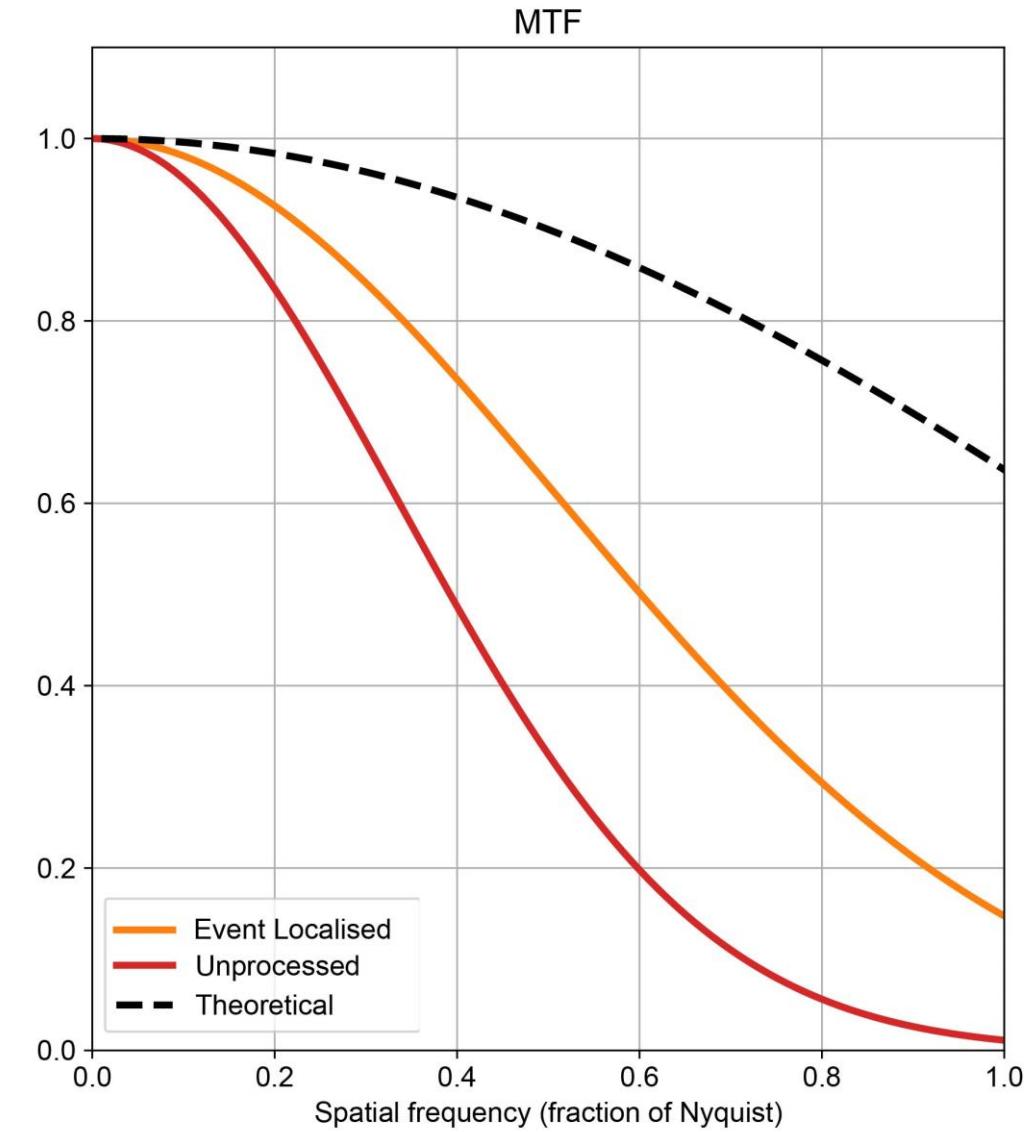
Timepix3 for cryo-EM

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Validation: Modulation Transfer Function (MTF)



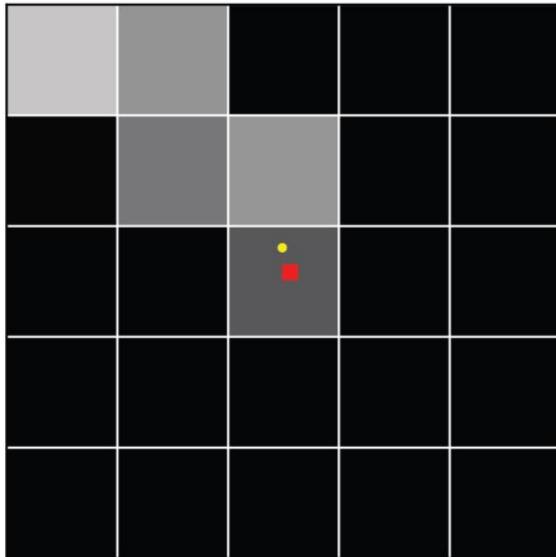
Uncorrected and corrected image of
UltrAU grid foil (225x)



Deterministic Blur

$$DQE = \frac{SNR_{in}^2}{SNR_{out}^2} = DQE(0) \frac{MTF^2(\omega)}{NNPS(\omega)}$$

DQE = Detective Quantum Efficiency
SNR = Signal to Noise Ratio
NNPS = Normalised Noise Power Spectrum
MTF = Modulation Transfer Function



Unprocessed Timepix3 output
Simulated incident position
Predicted incident position



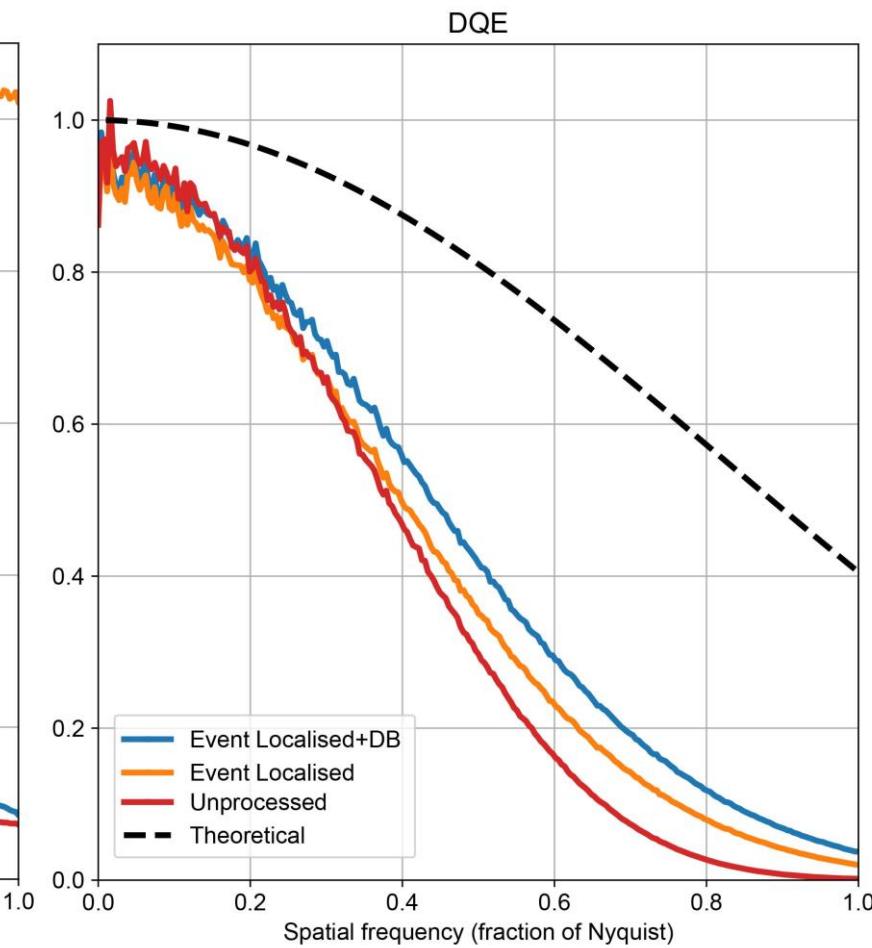
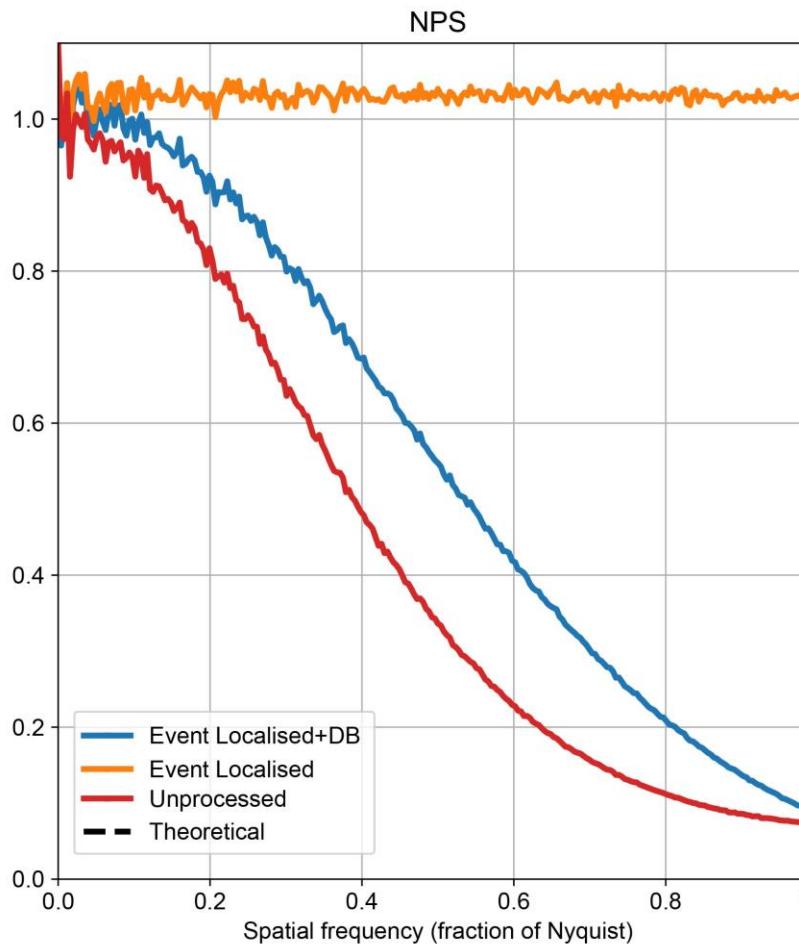
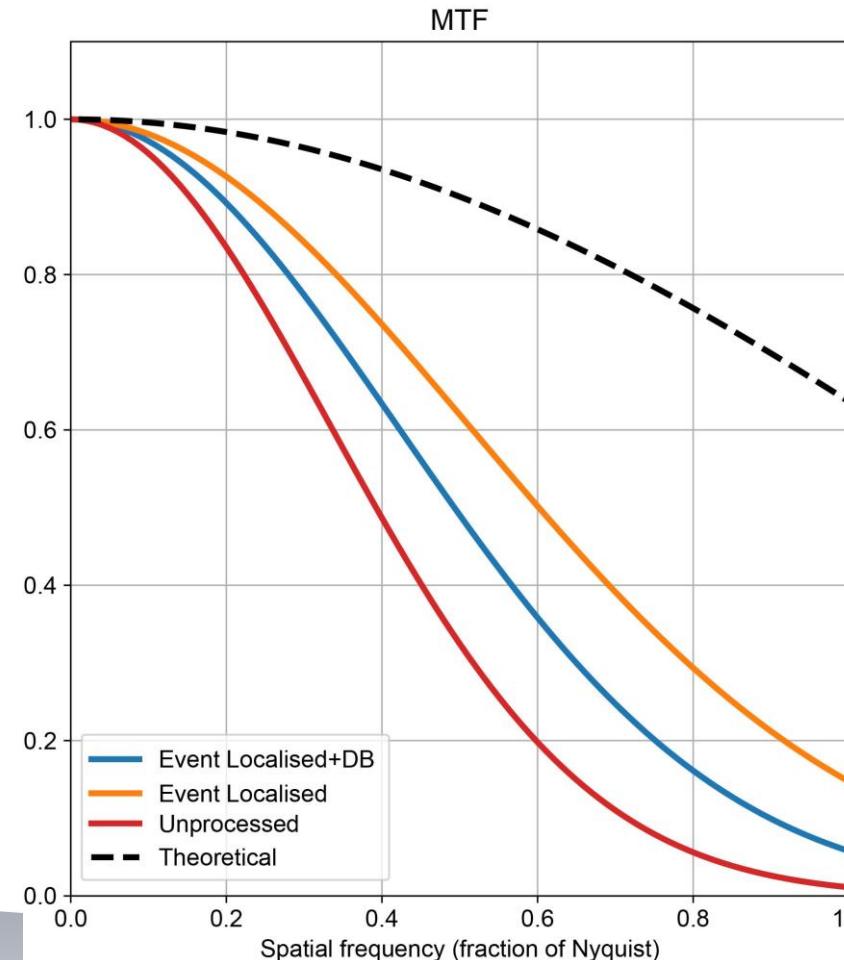
Simulated incident position



Predicted incident position

Validation: Detective Quantum Efficiency (DQE)

$$DQE = \frac{SNR_{in}^2}{SNR_{out}^2} = DQE(0) \frac{MTF^2(\omega)}{NNPS(\omega)}$$

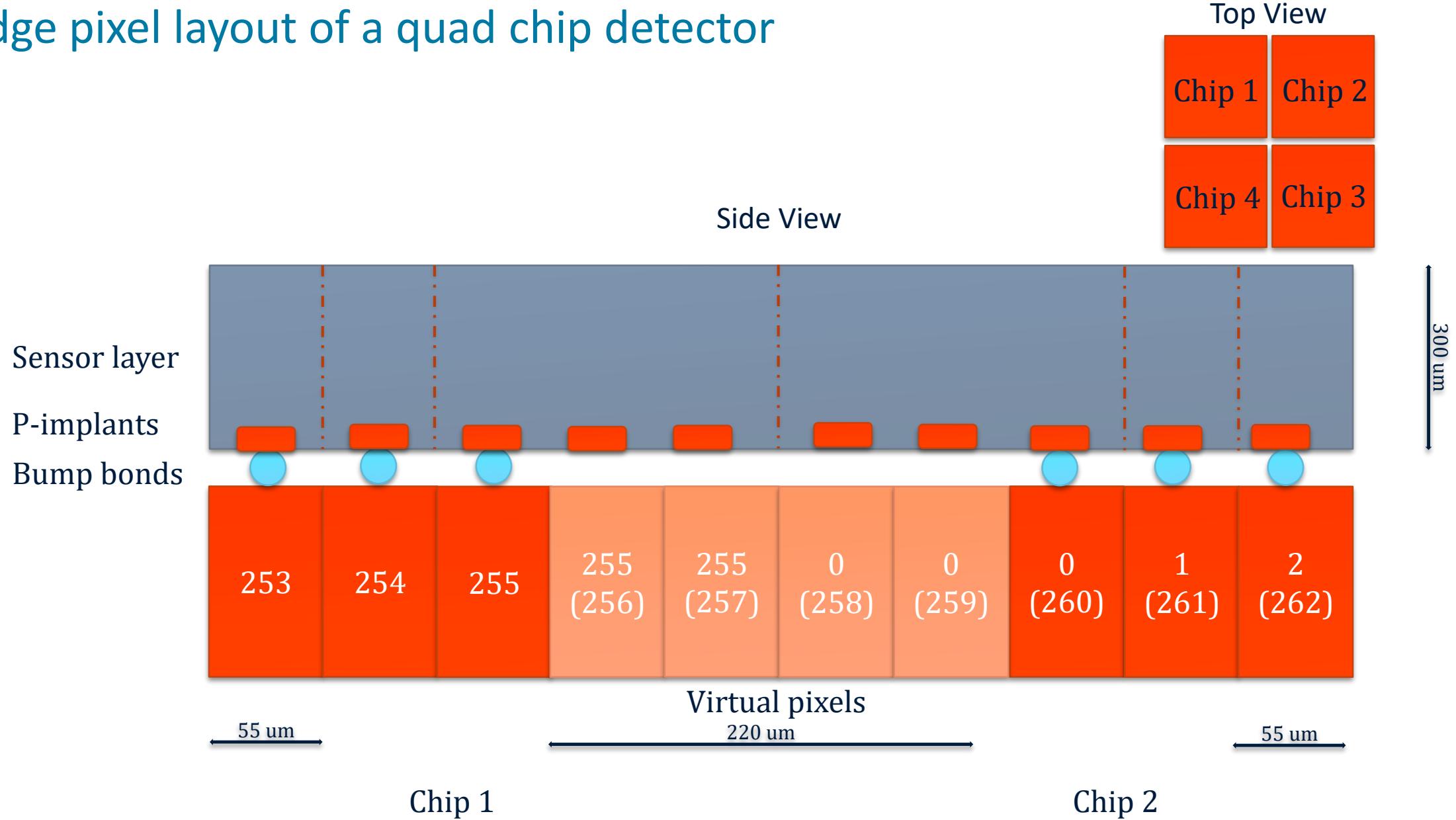


DQE(0) from Paton et al., 2021.

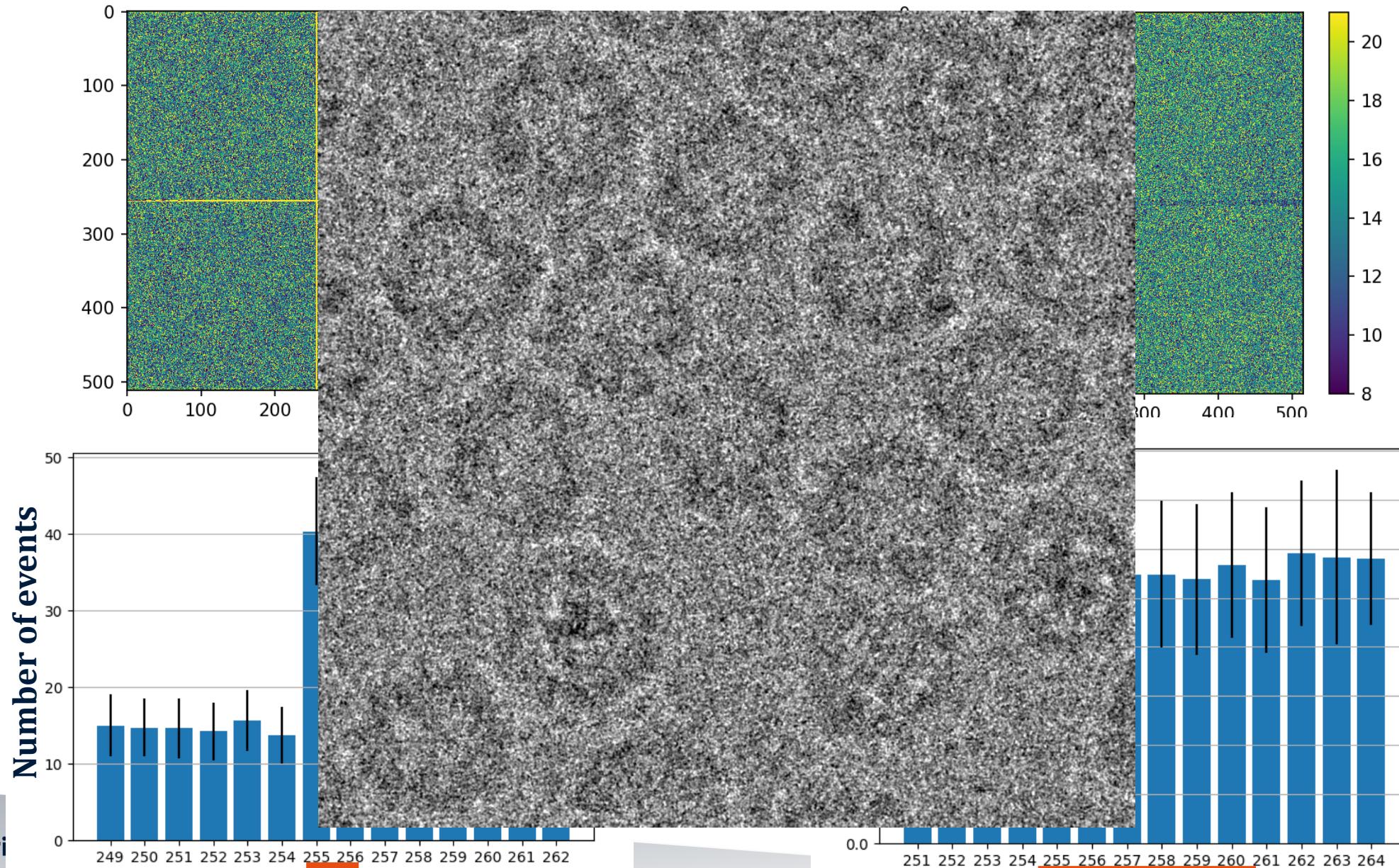
Timepix3 for cryo-EM

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Edge pixel layout of a quad chip detector



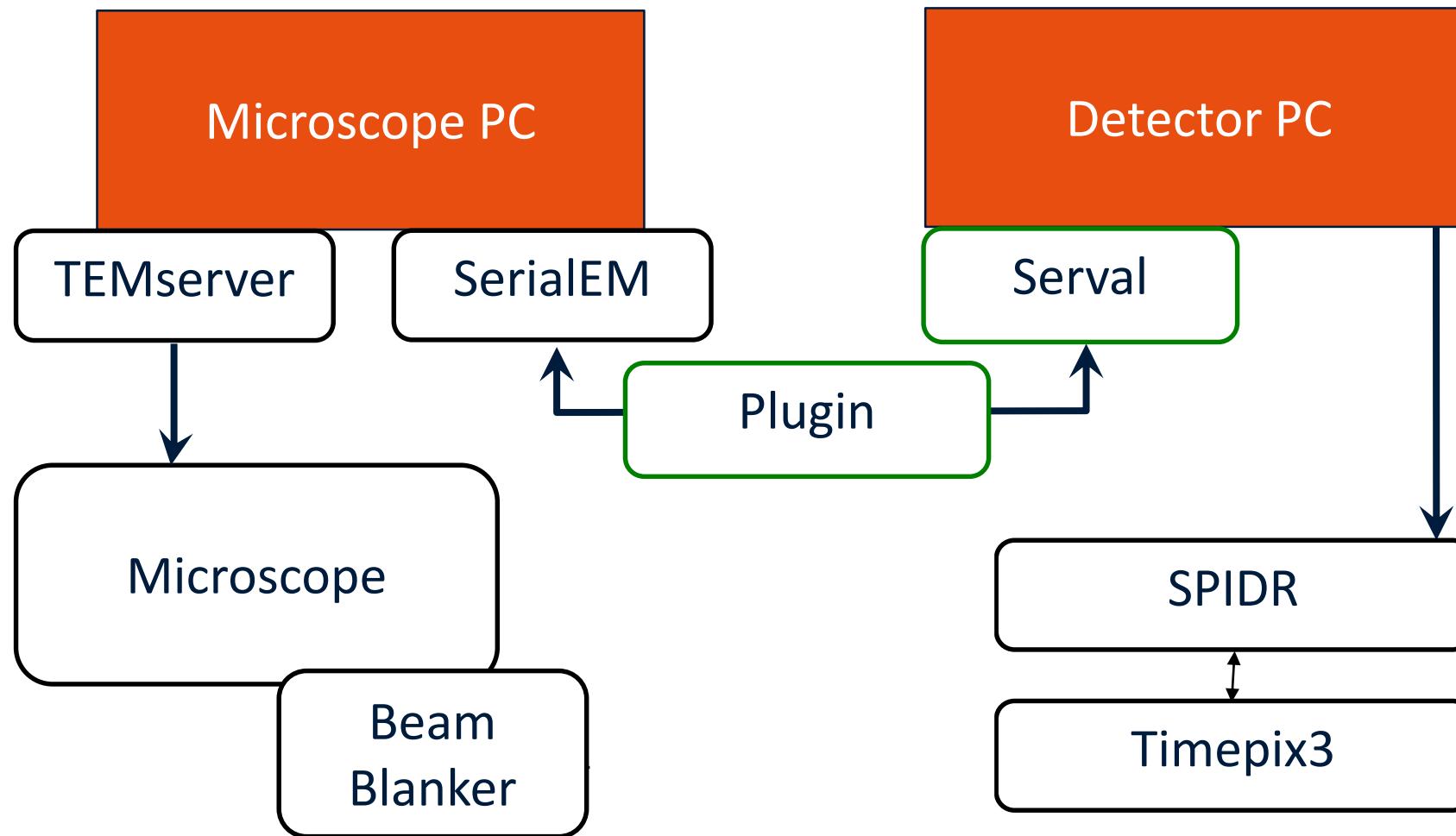
Correction for chip edge



Timepix3 for cryo-EM

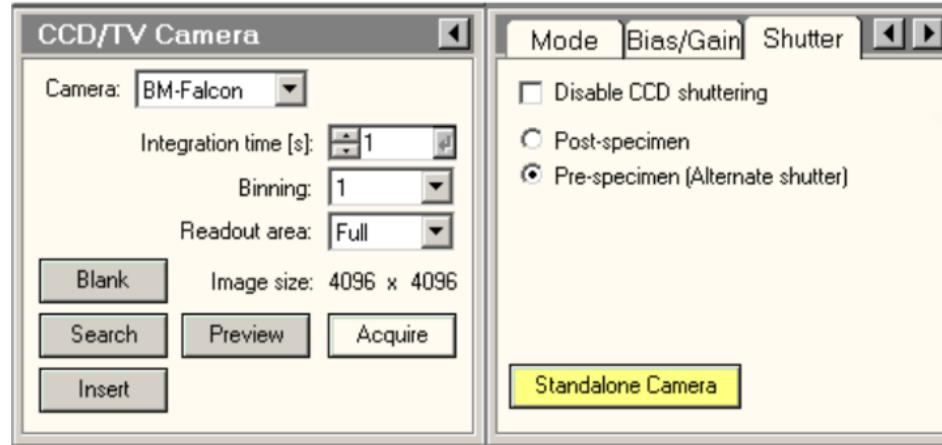
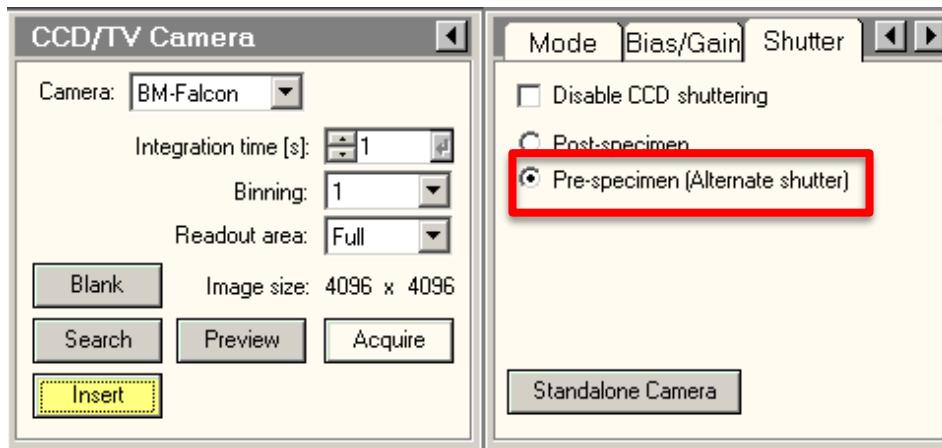
1. Event localisation of electrons
2. Measuring MTF, NPS and DQE
3. Correcting for chip edge
4. Integration of Timepix3 in SerialEM and microscope for automated data collection
5. Single particle analysis

Integrate Timepix3 and the Microscope



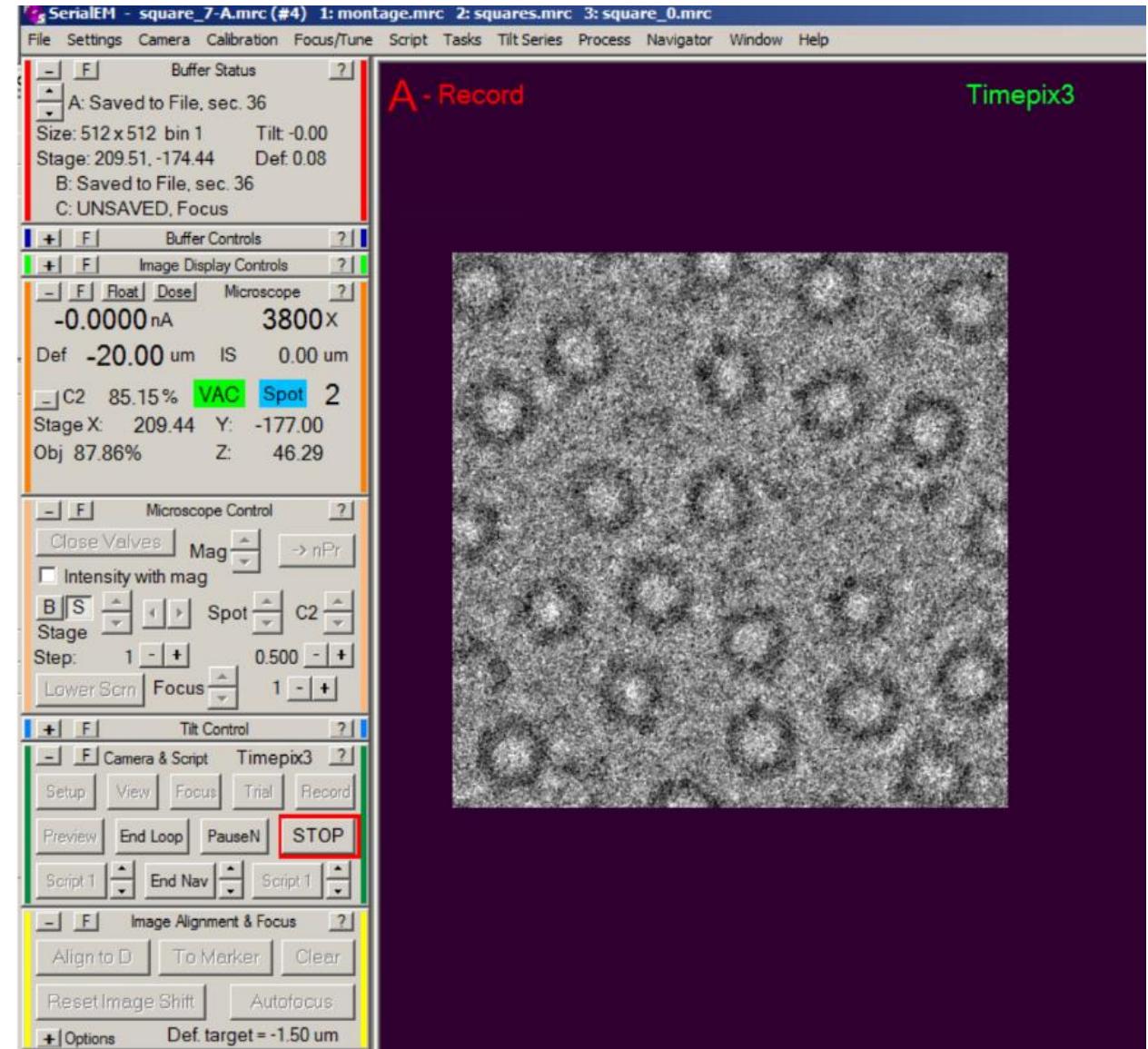
150 ms!

Integrate Timepix3 to the Microscope



< 0.3 ms!

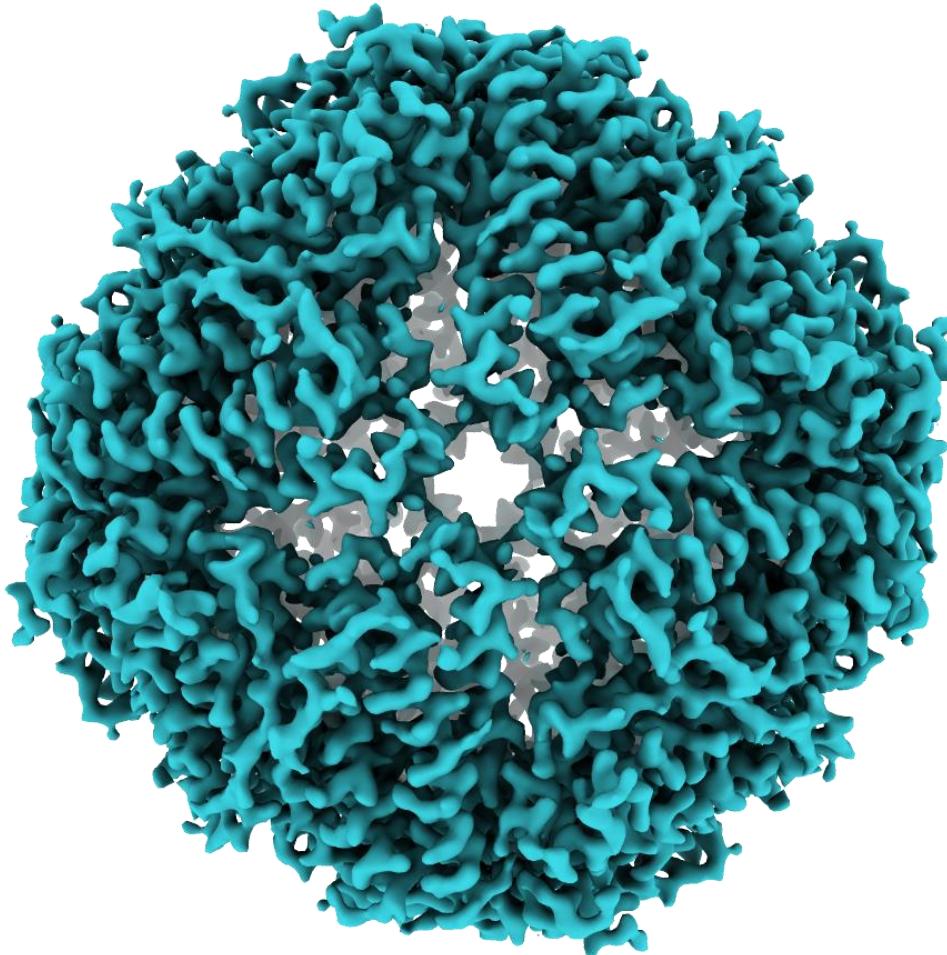
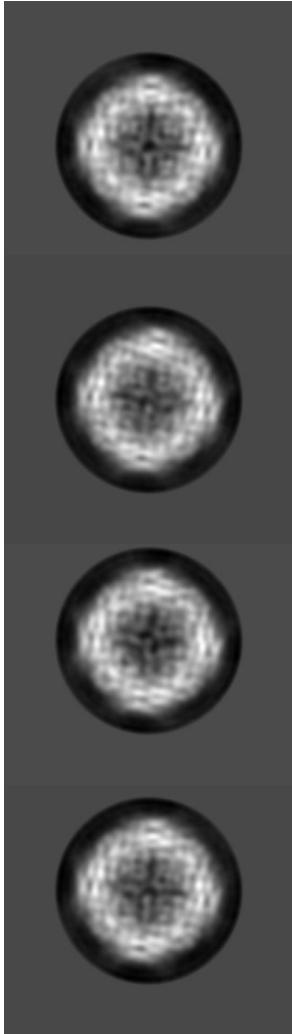
1.5s exposure /50 frames
1 frame is 30 ms
300 us is only 1% of the first frame!



Timepix3 for cryo-EM

1. Event localisation of electrons
2. Measuring MTF, NPS and DQE
3. Correcting for chip edge
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5. Single particle analysis

Single particle analysis with TPX3



3.05 Å map reconstruction of BfrB

Pixel size: 1.2 Å (215 kx)

Superres pixsize: 0.6 Å with Deterministic Blur

B-factor: -100

Exposure: 1.5s

Flux: 35 e/A²/s

Fluence: 50 e/A²

Event localised: CNN-ToT 2x super resolution

Microscope: FEI Tecnai Arctica (200 kV)

Protein reconstruction map resolution

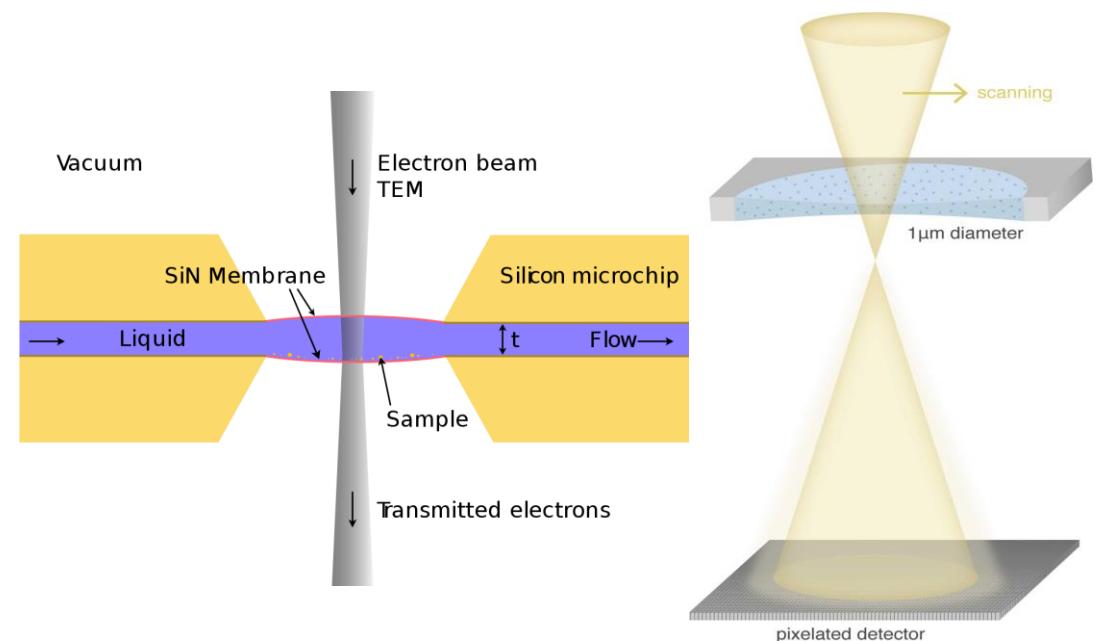
Unprocessed	
Nr. particles	10414
Resolution (Å)	3.85
B factor (Å ²)	-201

Summary

- Integrate Timepix3 to cryo-EM workflow
- Accurate event localisation of electrons using ToT (and ToA) data using a convolutional neural network
- MTF and DQE improvement from event localisation
- Timepix3 is a versatile detector for diverse cryo-EM workflows

Outlook

- Improving event localisation
- Analyse first few moments of exposure
- Liquid cell electron microscopy
- Cryo Ptychography



Acknowledgments



Paul van Schayck

Raimond Ravelli

Kevin Knoops

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Abril Gijsbers

Carmen Lopez-Iglesias

Ron Heeren



Erik Maddox

Erik Hogenbirk

Bram Bouwens

Dmitry Byelov

Leon van Velzen

Walter van Bodegom

Jord Prangsma



Rafal Dunin-Borkowski

Penghan Lu

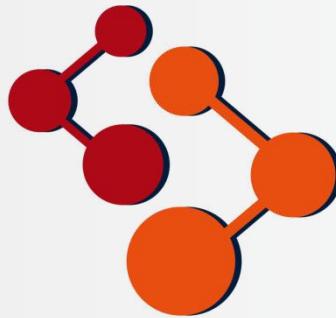
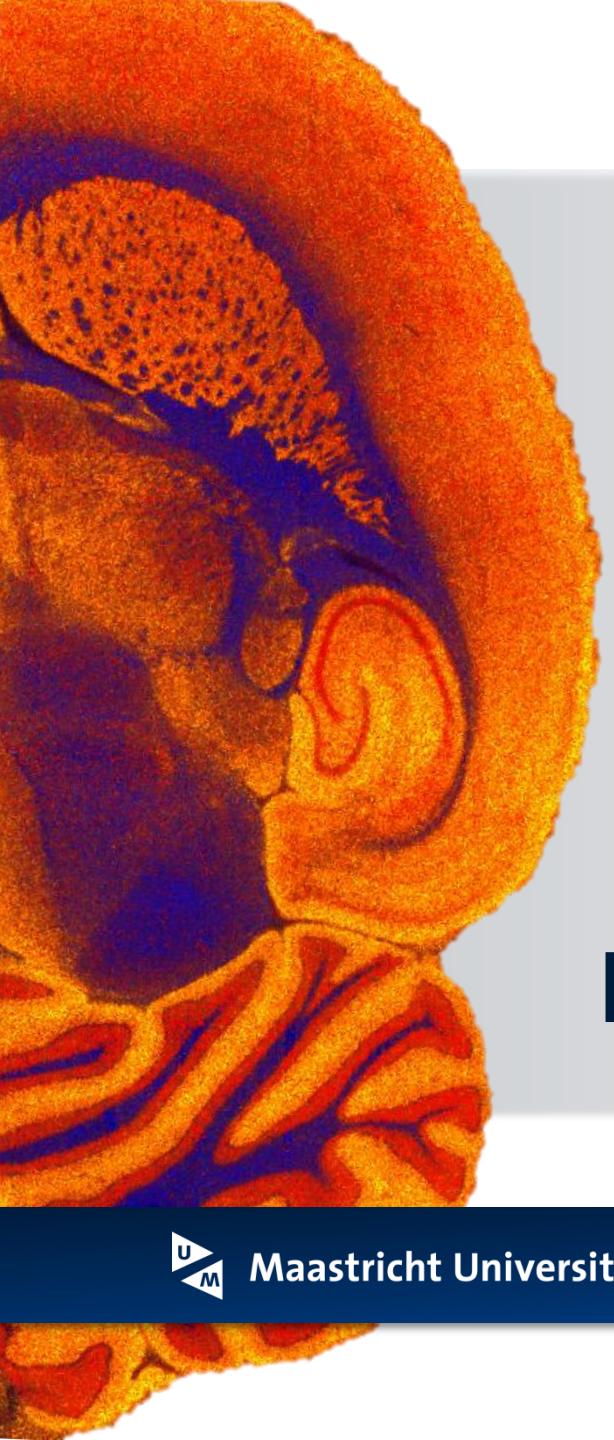
Dieter Weber

Alexander Clausen



Laurent Schijns



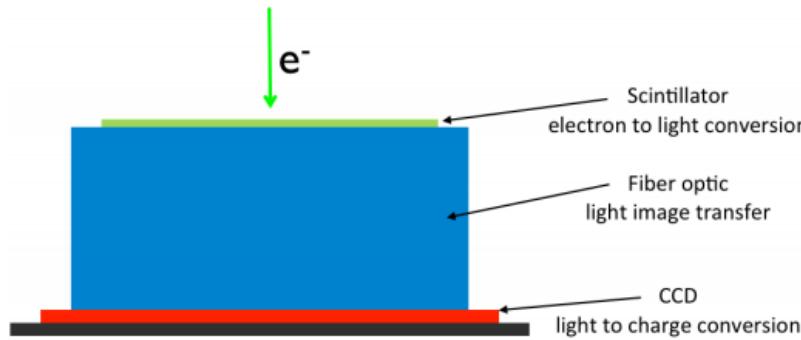


M4I

MAASTRICHT FOR IMAGING

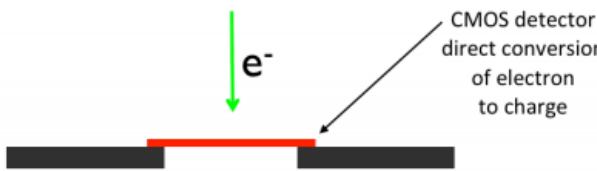
Type of electron detectors

Charge Coupled Device (CCD)



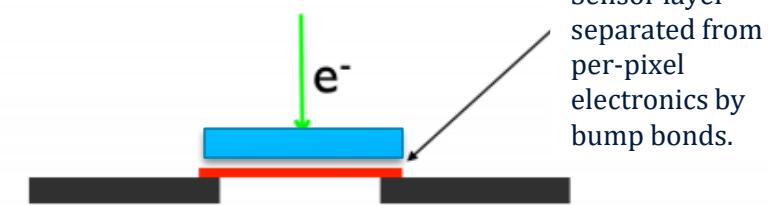
Scintillator adds noise
Scintillator deteriorate PSF
Limited dynamic range
Readout noise

Monolithic Active Pixel Sensor (MAPS)



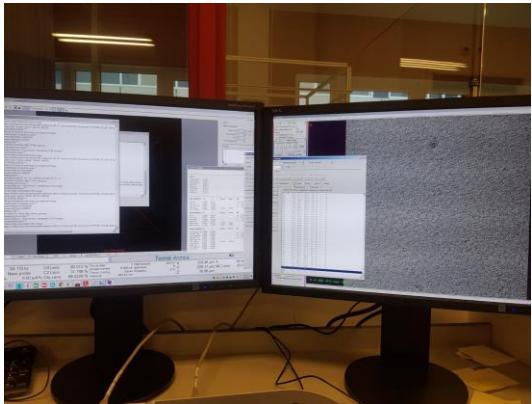
Frame based
Low throughput ~ 40 s
0.01–0.025 electrons/pixel/frame
Works best at 300 kV
Radiation sensitive
Limited dynamic range

Timepix3 Hybrid Pixel Detector

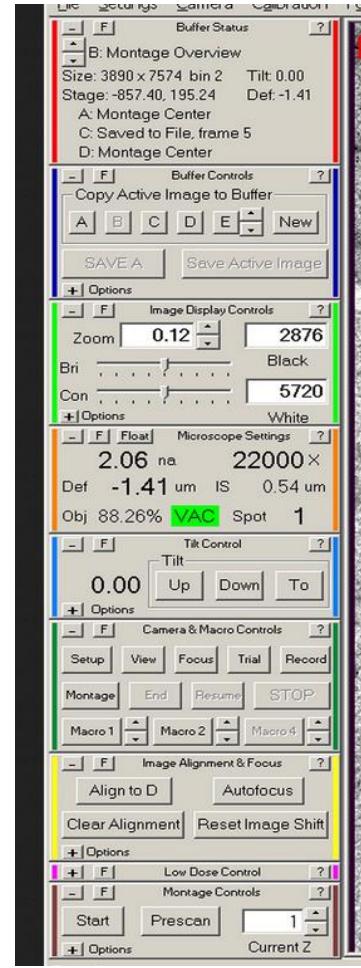


True counting detector
Throughput: < 1 second
Can work at all energies

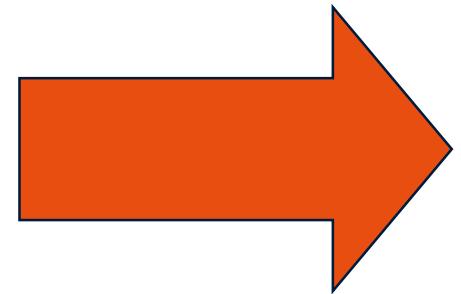
Triggering the beam blunker 1



Microscope PC

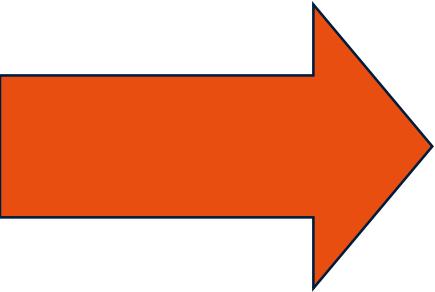


SerialEM

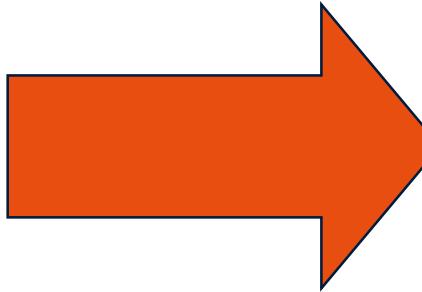


Serval

Triggering the beam blanker 2



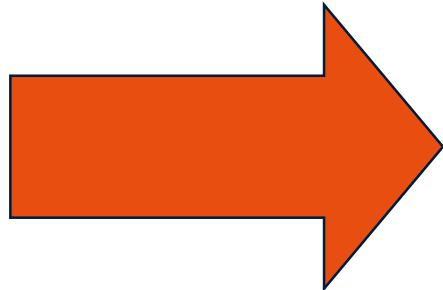
Timepix3 PC



10 gbit fiber
cable

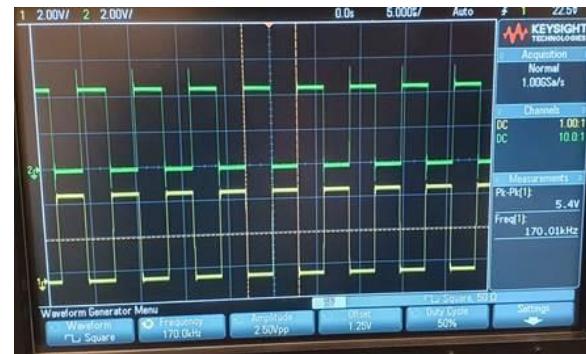


Timepix3 + SPIDR

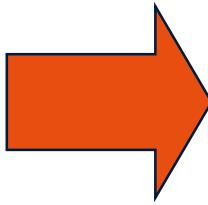


Open Shutter
(HDMI cable)

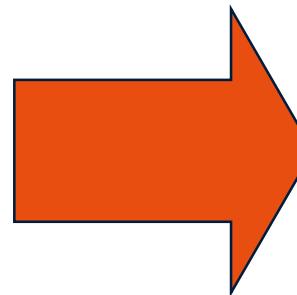
Triggering the beam blanker 3



Signal inversion



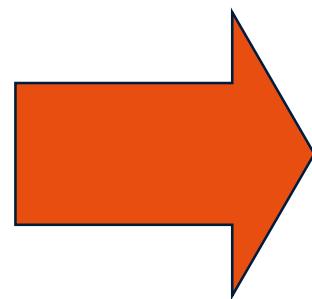
ASI TriggerBox



BNC



Microscope Blanker control

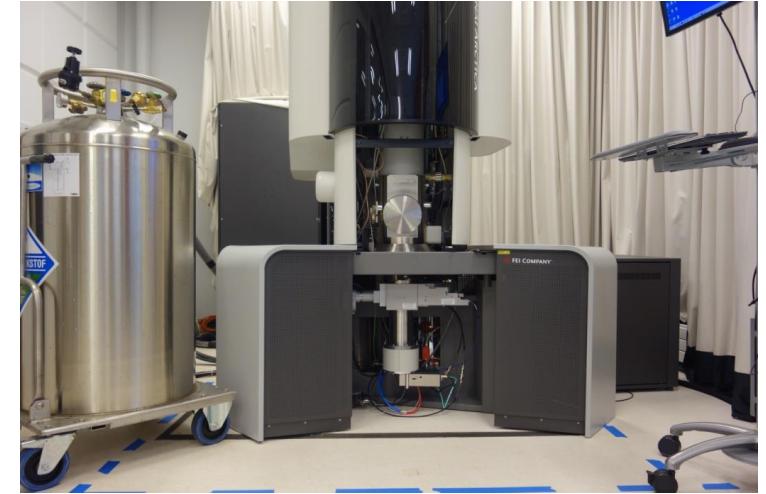
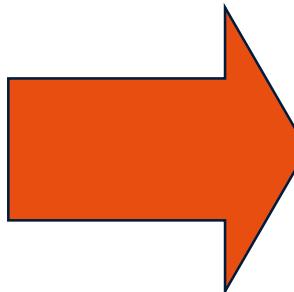


BNC

Triggering the beam blanker 4

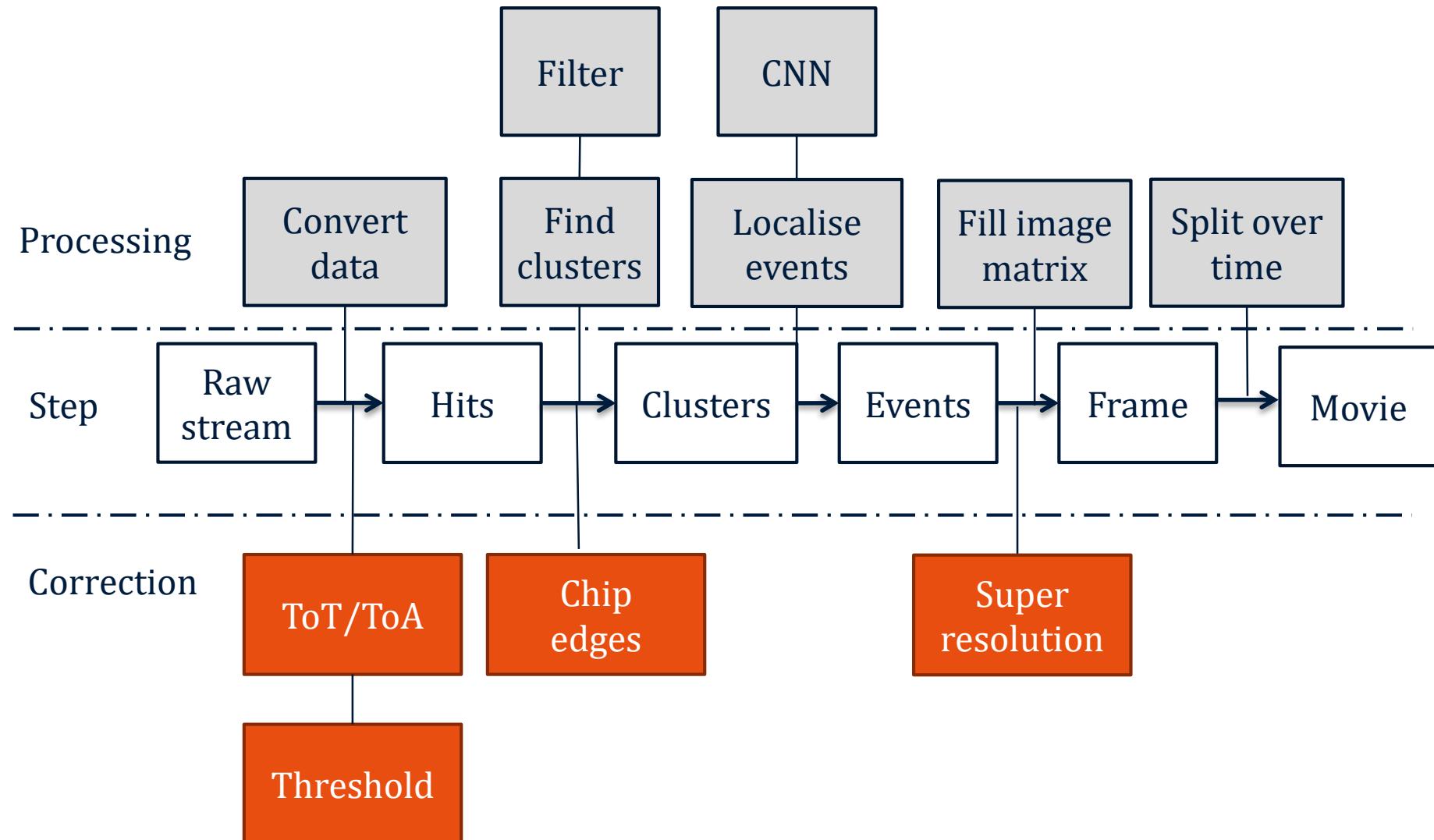


Microscope electronics box

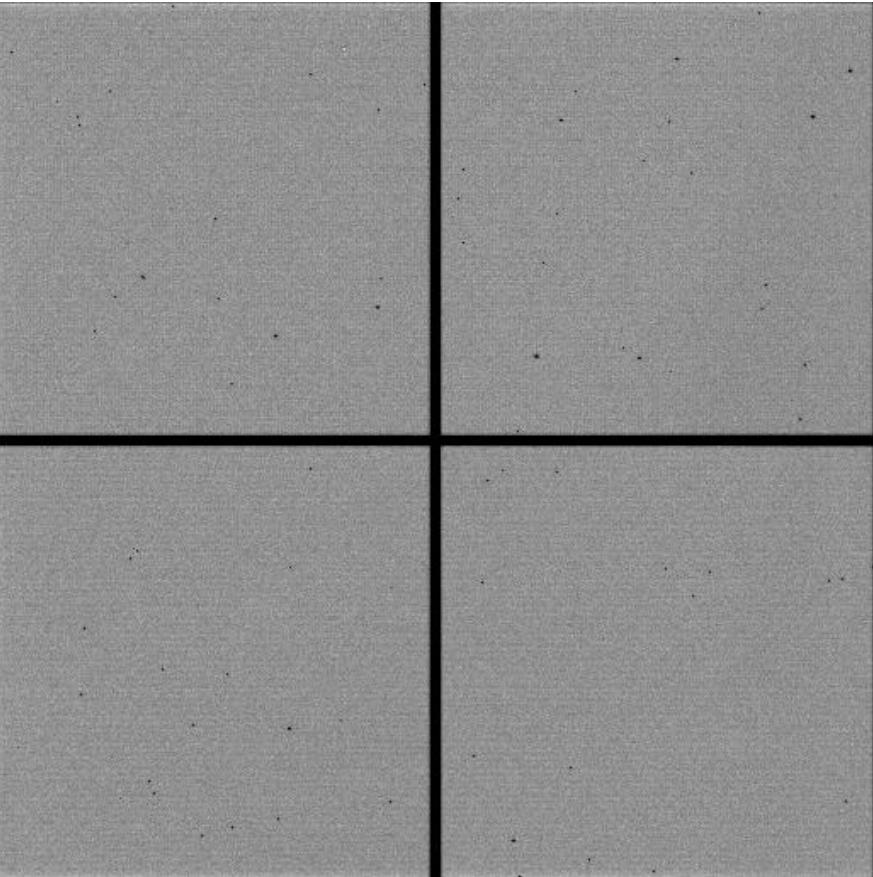


Beam deflector in microscope

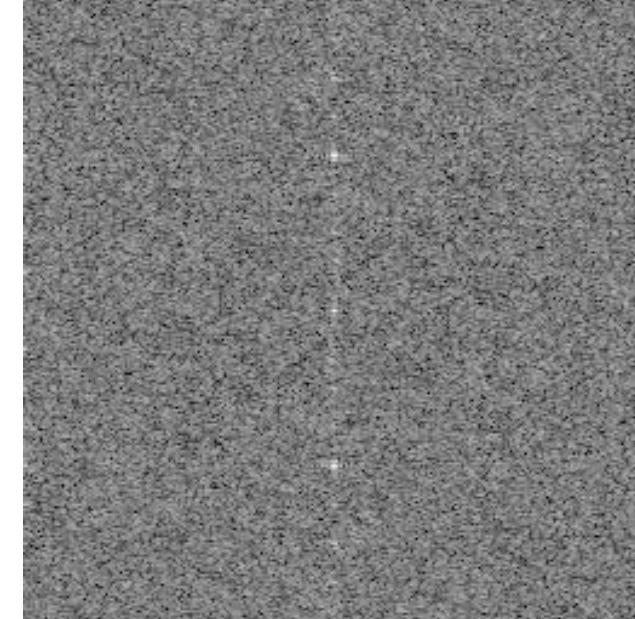
Data Processing



Systematic row pattern seen after CNN-ToT-ToA event localisation

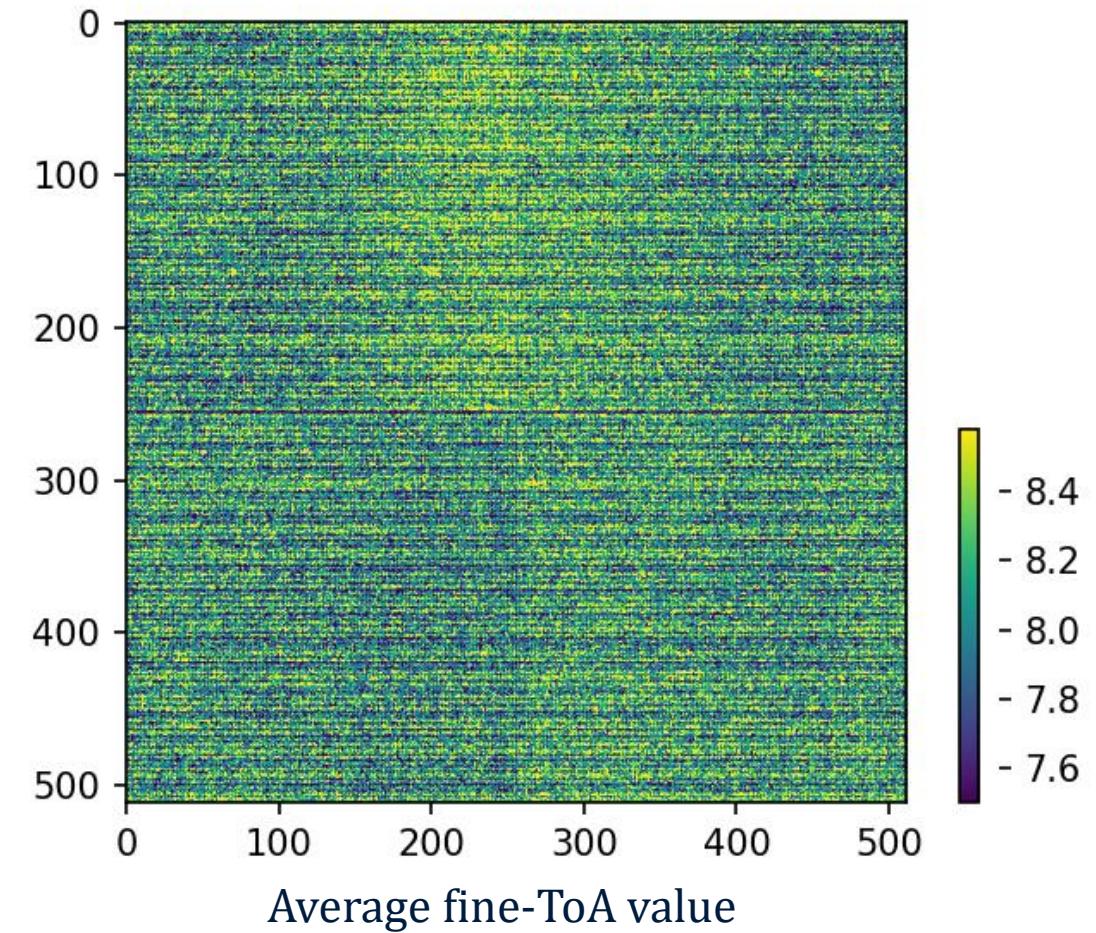
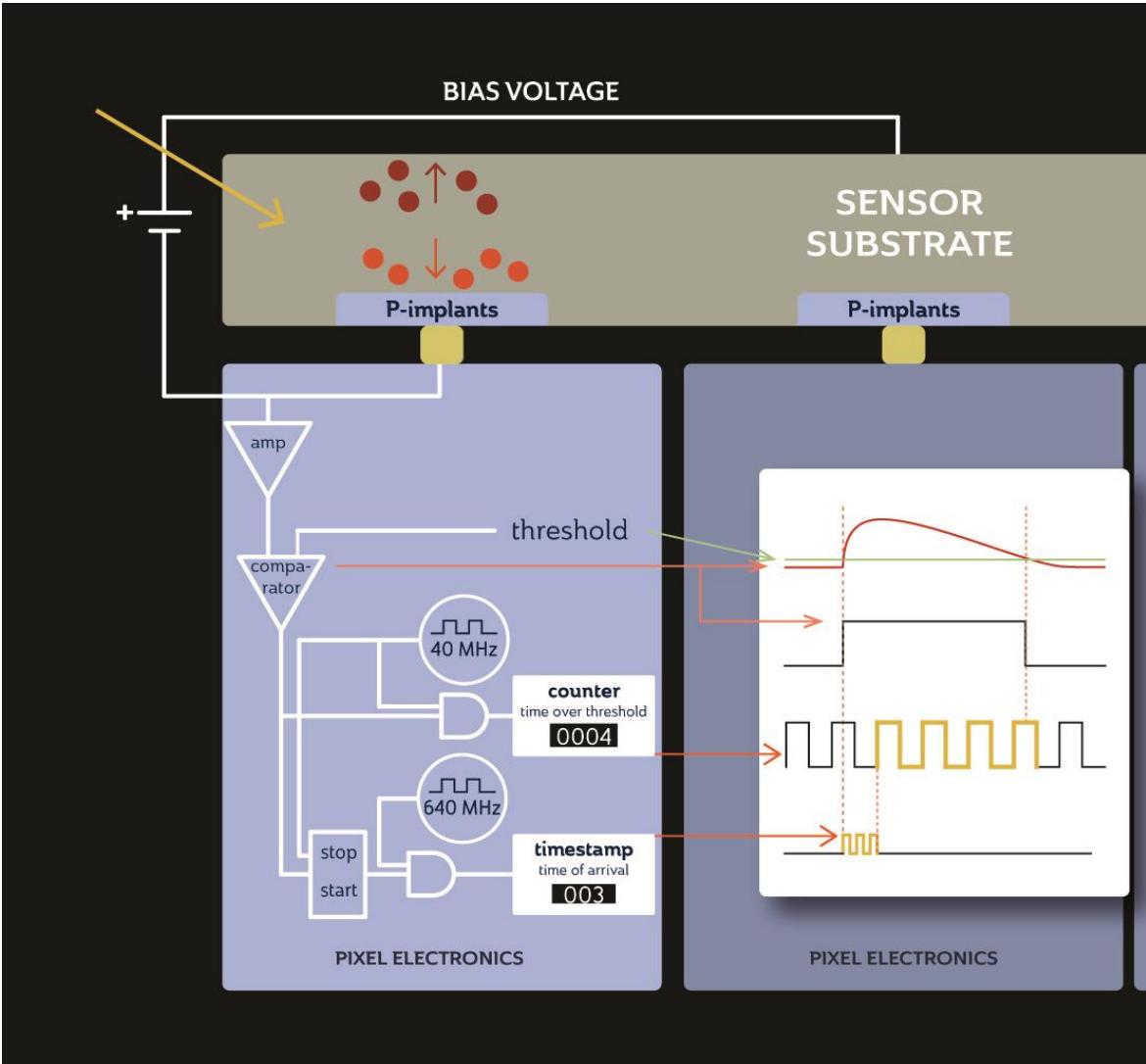


200 kV flat beam, with CNN-ToT-ToA event localisation



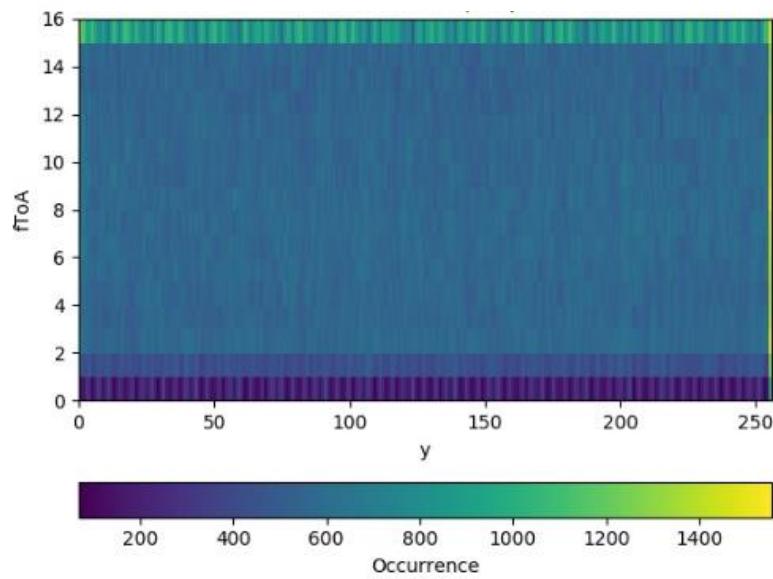
Power spectrum (FFT)

Systematic row pattern seen after CNN-ToT-ToA event localisation

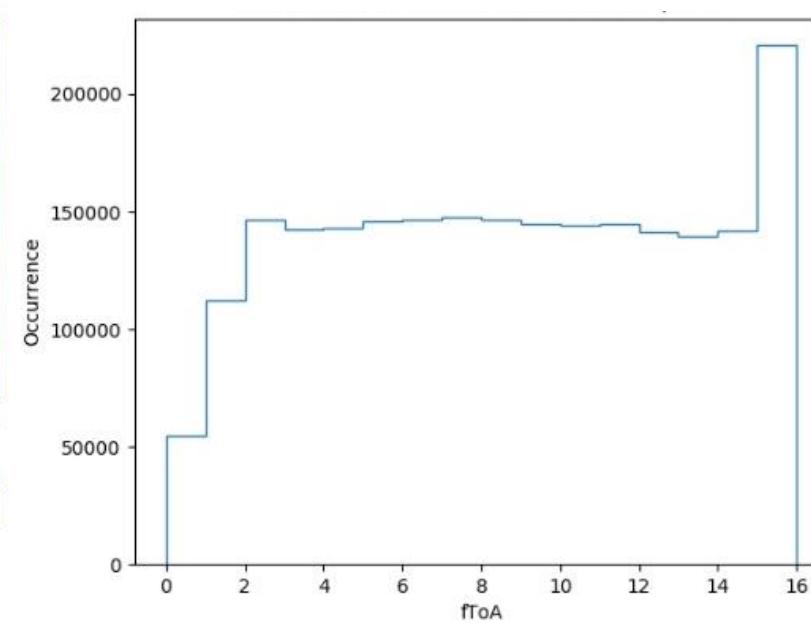


Pattern seen in fine-ToA timer of Timepix3

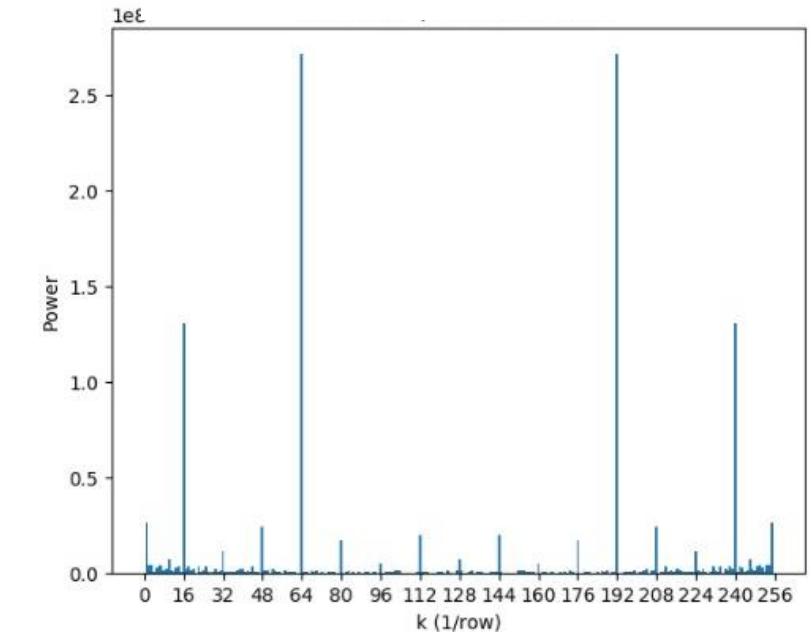
fToA distribution for each row



Overall fToA distribution

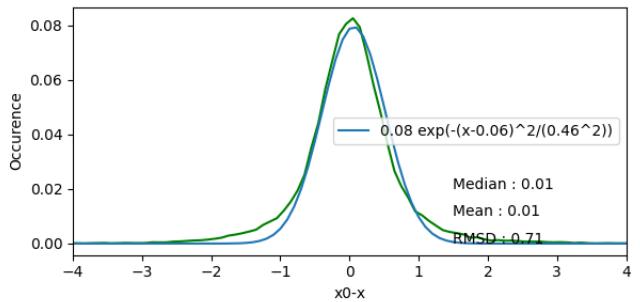
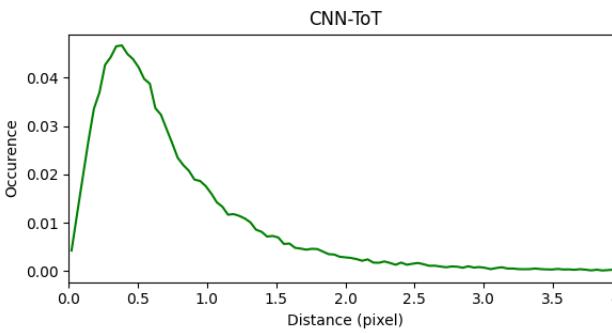
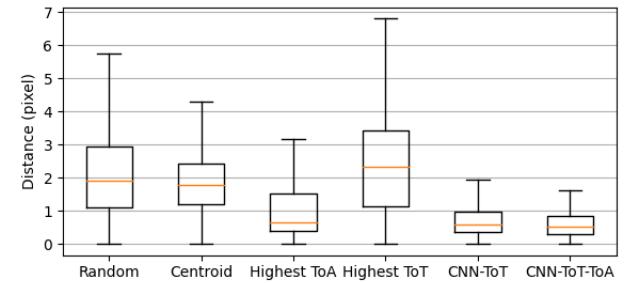


FFT of bin15 across the rows

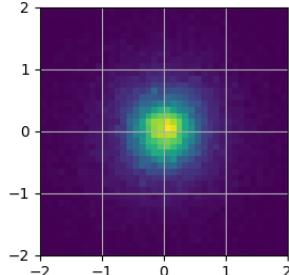


Due to phasing setting of the fine-ToA signal?

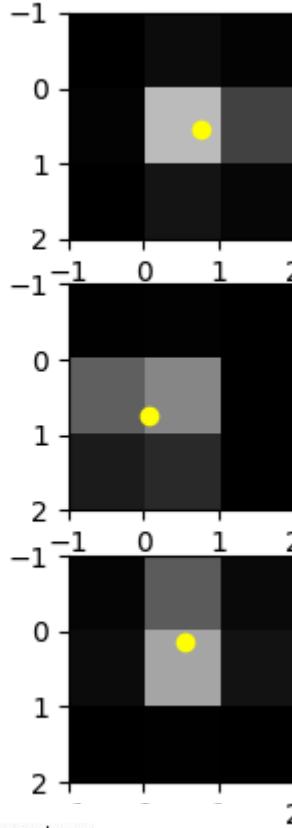
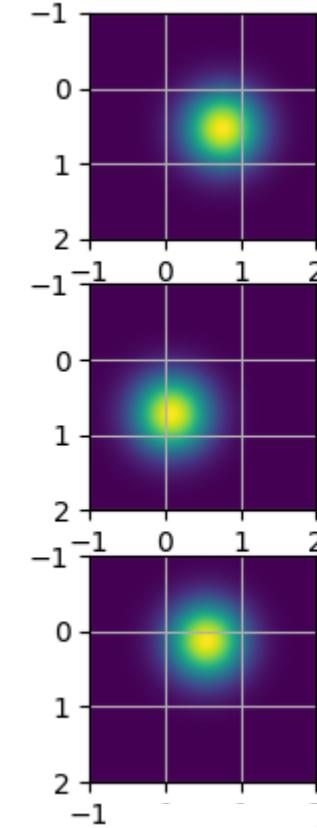
Gaussian event place backs



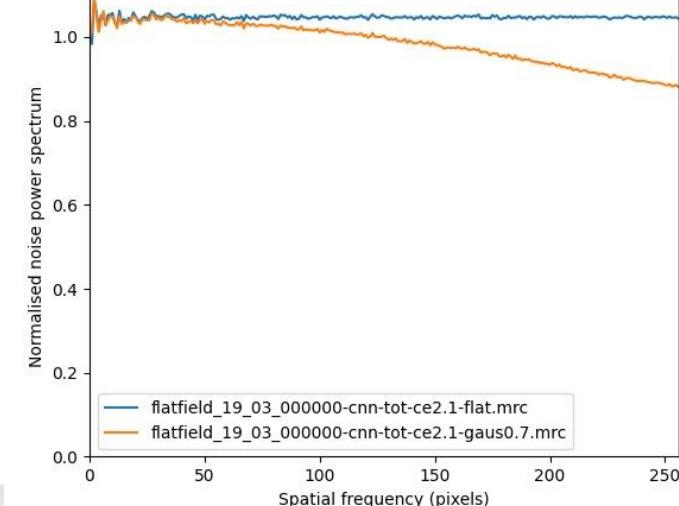
Simulated PSF



Binned simulated Gaussians



Normalised noise power spectrum

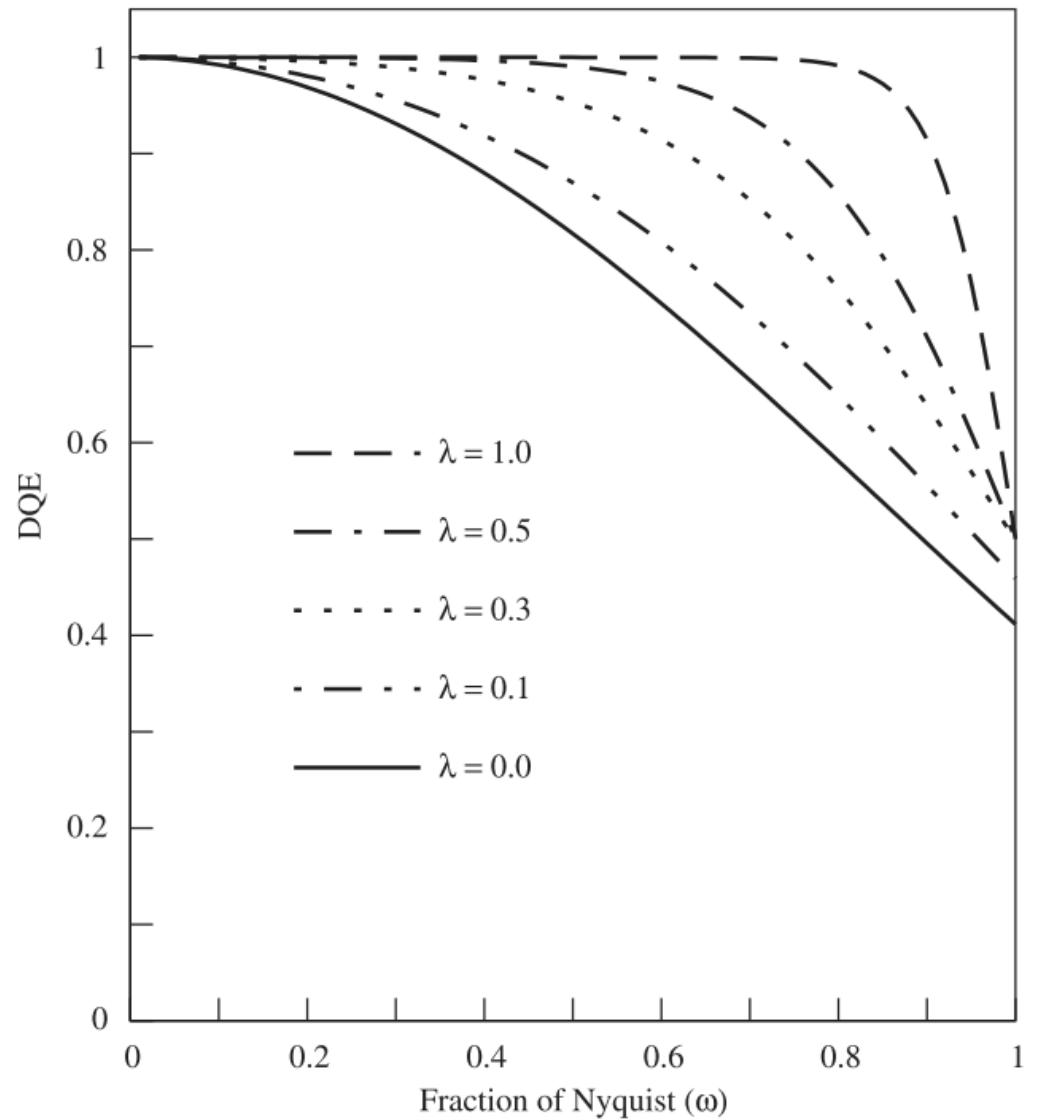


Deterministic blur

dimensional generalisation of Eq. (2). For an incident beam obeying Poisson statistics, with on average n electrons per pixel and giving an average output signal of d_n (so that the average signal per primary electron is d_n/n)

$$DQE(\omega) = \frac{d_n^2 MTF^2(\omega)}{nNPS_n(\omega)} \quad (3)$$

gain linear filter. In the absence of aliasing, deterministic blur does not affect the DQE [12] as the signal and noise terms are damped equally. The damping will however be greater for the aliased noise terms at higher frequency and so the relative reduction in their contribution leads to an increased DQE at higher spatial frequencies. This is illustrated by the calculation shown in Fig. 1 where the expected DQE is plotted as a function of spatial frequency for various amounts of deterministic blur in an otherwise perfect pixel detector. As the blurring reduces the signal, having low readout noise is essential. Although it can produce a useful improvement in DQE at 0.75 Nyquist, the DQE at Nyquist is always limited to at most 50%. It is important to stress that this result only applies if the reduction in MTF is due to deterministic blur. The effect will also be less when the input signal has an intrinsic width and hence a natural damping of higher spatial frequency components such as when the input signal is better described by a Gaussian with non-zero width rather than a delta function.



CNN-ToT vs Hits and Timepix 3 VS FalconIII EC

	Super resolution CNN-ToT	Hits
Nr. particles	7741	10414
Resolution (Å)	3.05	3.85
B factor (Å ²)	-100	-201

	Timepix 3	FalconIII EC
Nr. particles	7741	124577
Resolution (Å)	3.05	2.54
B factor (Å ²)	-100	-93
Nr. Micrographs	2977	979